



The MCF523x is a family of highly-integrated 32-bit microcontrollers based on the V2 ColdFire microarchitecture. Featuring a 16 or 32 channel eTPU, 64 Kbytes of internal SRAM, a 2-bank SDRAM controller, four 32-bit timers with dedicated DMA, a 4 channel DMA controller, up to 2 CAN modules, 3 UARTs and a queued SPI, the MCF523x family has been designed for general purpose industrial control applications. It is also a high-performance upgrade for users of the MC68332. This document provides an overview of the MCF523x microcontroller family, focusing on its highly diverse feature set, as well as providing an "at-a-glance" comparison to the MC68332.

The MCF523x family is based on the Version 2 ColdFire reduced instruction set computing (RISC) microarchitecture operating at a core frequency of up to 150 MHz and bus frequency up to 75 MHz.

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1 Overview

This 32-bit device's on-chip modules include:

- V2 ColdFire core with enhanced multiply-accumulate unit (EMAC) providing 144 Dhrystone 2.1 MIPS @ 150 MHz
- eTPU with 16 or 32 channels, 6 Kbytes of code memory and 1.5 Kbytes of data memory with Nexus Class 1 debug support
- 64 Kbytes of internal SRAM

MCF523x Family Configurations

- External bus speed of one half the CPU operating frequency (75 MHz bus @ 150 MHz core)
- 10/100 Mbps bus-mastering Ethernet controller
- 8 Kbytes of configurable instruction/data cache
- Three universal asynchronous receiver/transmitters (UARTs)
 - Optional second FlexCAN module multiplexed with the third UART
- Controller area network 2.0B (FlexCAN) module
- Inter-integrated circuit (I²C™) bus controller
- Queued serial peripheral interface (QSPI) module
- Hardware cryptography accelerator (optional)
 - Random number generator
 - DES/3DES/AES block cipher engine
 - MD5/SHA-1/HMAC accelerator
- Four channel 32-bit direct memory access (DMA) controller
- Four channel 32-bit input capture/output compare timers with optional DMA support
- Four channel 16-bit periodic interrupt timers (PITs)
- Programmable software watchdog timer
- Interrupt controller capable of handling up to 126 interrupt sources
- Clock module with integrated phase locked loop (PLL)
- External bus interface module including a 2-bank synchronous DRAM controller
- 32-bit non-multiplexed bus with up to 8 chip select signals that support paged mode Flash memories

1.1 MCF523x Family Configurations

Table 1. MCF523x Family Configurations

Module	5232	5233	5234	5235
ColdFire V2 Core with EMAC (Enhanced Multiply-Accumulate Unit)	x	x	x	x
Enhanced Time Processor Unit with memory (eTPU)	16-ch 6K	32-ch 6K	16-ch 6K	16-ch 6K
System Clock	up to 150 MHz			
Performance (Dhrystone/2.1 MIPS)	up to 144			
Instruction/Data Cache	8 Kbytes			
Static RAM (SRAM)	64 Kbytes			
Interrupt Controllers (INTC)	2	2	2	2
Edge Port Module (EPORT)	x	x	x	x
External Interface Module (EIM)	x	x	x	x

Table 1. MCF523x Family Configurations (continued)

Module	5232	5233	5234	5235
4-channel Direct-Memory Access (DMA)	x	x	x	x
SDRAM Controller	x	x	x	x
Fast Ethernet Controller (FEC)	—	—	x	x
Cryptography - Security module for data packets processing	—	—	—	x
Watchdog Timer (WDT)	x	x	x	x
Four Periodic Interrupt Timers (PIT)	x	x	x	x
32-bit DMA Timers	4	4	4	4
QSPI	x	x	x	x
UART(s)	3	3	3	3
I ² C	x	x	x	x
FlexCAN 2.0B - Controller-Area Network communication module	1	2	1	2
General Purpose I/O Module (GPIO)	x	x	x	x
JTAG - IEEE 1149.1 Test Access Port	x	x	x	x
Package	160 QFP 196 MAPBGA	256 MAPBGA	256 MAPBGA	256 MAPBGA

1.2 Block Diagram

The superset device in the MCF523x family comes in a 256 mold array process ball grid array (MAPBGA) package. Figure 1 shows a top-level block diagram of the MCF5235, the superset device.

1.3 Features

This document contains information on a new product under development. Specifications and information herein are subject to change without notice.

1.3.1 Feature Overview

- Version 2 ColdFire variable-length RISC processor core
 - Static operation
 - 32-bit address and data path on-chip
 - Processor core runs at twice the bus frequency
 - Sixteen general-purpose 32-bit data and address registers
 - Implements the ColdFire Instruction Set Architecture, ISA_A, with extensions to support the user stack pointer register, and 4 new instructions for improved bit processing
 - Enhanced Multiply-Accumulate (EMAC) unit with four 48-bit accumulators to support 32-bit signal processing algorithms
 - Illegal instruction decode that allows for 68K emulation support
- Enhanced Time Processor Unit (eTPU)
 - Event triggered VLIW processor timer subsystem
 - 32 channels
 - 24-bit timer resolution
 - 6 Kbyte of code memory and 1.5 Kbyte of data memory
 - Variable number of parameters allocatable per channel
 - Double match/capture channels
 - Angle mode support
 - DMA and interrupt request support
 - Nexus Class 1 Debug support
- System debug support
 - Integrated debug supports both ColdFire Debug and Nexus class 1 features on a single port with cross triggering operations for ease of use
 - Unified programming model including both ColdFire and Nexus debug registers
 - Real time trace for determining dynamic execution path
 - Background debug mode (BDM) for in-circuit debugging
 - Real time debug support, with two user-visible hardware breakpoint registers (PC and address with optional data) that can be configured into a 1- or 2-level trigger
- On-chip memories
 - 8-Kbyte cache, configurable as instruction-only, data-only, or split I-/D-cache
 - 64-Kbyte dual-ported SRAM on CPU internal bus, accessible by core and non-core bus masters (e.g., DMA, FEC)
- Fast Ethernet Controller (FEC)
 - 10 BaseT capability, half duplex or full duplex

Features

- 100 BaseT capability, half duplex or full duplex
- On-chip transmit and receive FIFOs
- Built-in dedicated DMA controller
- Memory-based flexible descriptor rings
- Media independent interface (MII) to external transceiver (PHY)
- FlexCAN Modules (up to 2)
 - Full implementation of the CAN protocol specification version 2.0B
 - Standard Data and Remote Frames (up to 109 bits long)
 - Extended Data and Remote Frames (up to 127 bits long)
 - 0–8 bytes data length
 - Programmable bit rate up to 1 Mbit/sec
 - Flexible Message Buffers (MBs), totalling up to 16 message buffers of 0–8 bytes data length each, configurable as Rx or Tx, all supporting standard and extended messages
 - Unused MB space can be used as general purpose RAM space
 - Listen only mode capability
 - Content-related addressing
 - Three programmable mask registers: global (for MBs 0-13), special for MB14 and special for MB15
 - Programmable transmit-first scheme: lowest ID or lowest buffer number
 - “Time stamp” based on 16-bit free-running timer
 - Global network time, synchronized by a specific message
- Three Universal Asynchronous Receiver Transmitters (UARTs)
 - 16-bit divider for clock generation
 - Interrupt control logic
 - Maskable interrupts
 - DMA support
 - Data formats can be 5, 6, 7 or 8 bits with even, odd or no parity
 - Up to 2 stop bits in 1/16 increments
 - Error-detection capabilities
 - Modem support includes request-to-send (\overline{URTS}) and clear-to-send (\overline{UCTS}) lines for two UARTs
 - Transmit and receive FIFO buffers
- I²C Module
 - Interchip bus interface for EEPROMs, LCD controllers, A/D converters, and keypads
 - Fully compatible with industry-standard I²C bus
 - Master or slave modes support multiple masters
 - Automatic interrupt generation with programmable level
- Queued Serial Peripheral Interface (QSPI)
 - Full-duplex, three-wire synchronous transfers

- Up to four chip selects available
- Master mode operation only
- Programmable master bit rates
- Up to 16 pre-programmed transfers
- Four 32-bit DMA Timers
 - 13-ns resolution at 75 MHz
 - Programmable sources for clock input, including an external clock option
 - Programmable prescaler
 - Input-capture capability with programmable trigger edge on input pin
 - Output-compare with programmable mode for the output pin
 - Free run and restart modes
 - Maskable interrupts on input capture or reference-compare
 - DMA trigger capability on input capture or reference-compare
- Four Periodic Interrupt Timers (PITs)
 - 16-bit counter
 - Selectable as free running or count down
- Software Watchdog Timer
 - 16-bit counter
 - Low power mode support
- Phase Locked Loop (PLL)
 - Crystal or external oscillator reference
 - 8 to 25 MHz reference frequency for normal PLL mode
 - 24 to 75 MHz oscillator reference frequency for 2:1 mode
 - Separate clock output pin
- Interrupt Controllers (x2)
 - Support for up to 110 interrupt sources organized as follows:
 - 103 fully-programmable interrupt sources
 - 7 fixed-level external interrupt sources
 - Unique vector number for each interrupt source
 - Ability to mask any individual interrupt source or all interrupt sources (global mask-all)
 - Support for hardware and software interrupt acknowledge (IACK) cycles
 - Combinatorial path to provide wake-up from low power modes
- DMA Controller
 - Four fully programmable channels
 - Dual-address and single-address transfer support with 8-, 16- and 32-bit data capability along with support for 16-byte (4×32 -bit) burst transfers
 - Source/destination address pointers that can increment or remain constant
 - 24-bit byte transfer counter per channel

Features

- Auto-alignment transfers supported for efficient block movement
- Bursting and cycle steal support
- Software-programmable connections between the 12 DMA requesters in the UARTs (3), 32-bit timers (4) plus external logic (4) the four DMA channels and the eTPU (1)
- External Bus Interface
 - Glueless connections to external memory devices (e.g., SRAM, Flash, ROM, etc.)
 - SDRAM controller supports 8-, 16-, and 32-bit wide memory devices
 - Support for n-1-1-1 burst fetches from page mode Flash
 - Glueless interface to SRAM devices with or without byte strobe inputs
 - Programmable wait state generator
 - 32-bit bidirectional data bus
 - 24-bit address bus
 - Up to eight chip selects available
 - Byte/write enables (byte strobes)
 - Ability to boot from external memories that are 8, 16, or 32 bits wide
- Chip Integration Module (CIM)
 - System configuration during reset
 - Selects one of four clock modes
 - Sets boot device and its data port width
 - Configures output pad drive strength
 - Unique part identification number and part revision number
 - Reset
 - Separate reset in and reset out signals
 - Six sources of reset: Power-on reset (POR), External, Software, Watchdog, PLL loss of clock, PLL loss of lock
 - Status flag indication of source of last reset
- General Purpose I/O interface
 - Up to 142 bits of general purpose I/O
 - Bit manipulation supported via set/clear functions
 - Unused peripheral pins may be used as extra GPIO
- JTAG support for system level board testing

1.3.2 V2 Core Overview

The processor core is comprised of two separate pipelines that are decoupled by an instruction buffer. The two-stage Instruction Fetch Pipeline (IFP) is responsible for instruction-address generation and instruction fetch. The instruction buffer is a first-in-first-out (FIFO) buffer that holds prefetched instructions awaiting execution in the Operand Execution Pipeline (OEP). The OEP includes two pipeline stages. The first stage decodes instructions and selects operands (DSOC); the second stage (AGEX) performs instruction execution and calculates operand effective addresses, if needed.

The V2 core implements the ColdFire Instruction Set Architecture Revision A with added support for a separate user stack pointer register and four new instructions to assist in bit processing. Additionally, the MCF523x core includes the enhanced multiply-accumulate unit (EMAC) for improved signal processing capabilities. The EMAC implements a 4-stage execution pipeline, optimized for 32×32 bit operations, with support for four 48-bit accumulators. Supported operands include 16- and 32-bit signed and unsigned integers as well as signed fractional operands as well as a complete set of instructions to process these data types. The EMAC provides superb support for execution of DSP operations within the context of a single processor at a minimal hardware cost.

1.3.3 Enhanced Time Processor Unit (eTPU)

The eTPU is an intelligent programmable I/O controller with its own core and memory system, allowing it to perform complex timing and I/O management independently of the CPU. The eTPU is essentially a co-processor designed for timing control, I/O handling, serial communications, motor control, and engine control applications and accesses data without the host CPU's intervention. Consequently, the host CPU setup and service times for each timer event are minimized or eliminated.

The eTPU is an enhanced version of the TPU module implemented on the MC68332 and MPC500 products. Enhancements of the eTPU include a more powerful processor which handles high-level C code efficiently and allows for more functionality and increased performance. Although there is no compatibility at microcode level, the eTPU maintains several features of older TPU versions and is conceptually almost identical. The eTPU library is a superset of the standard TPU library functions modified to take advantage of enhancements in the eTPU. These, along with a C compiler, make it relatively easy to port older applications. By providing source code for the Motorola library, it is possible for the eTPU to support the users own function development.

The eTPU has up to 32 timer channels in addition to having 6 Kbytes of code memory and 1.5 Kbytes of data memory that stores software modules downloaded at boot time and that can be mixed and matched as required for any specific application.

1.3.4 eTPU Functions

Any one of the following four sets of functions can be loaded into the device.

1.3.4.1 Set 1 (General)

- PWM – Full featured Pulse Width modulation
- ICOC – Input Capture / Output Compare
- PFM – Pulse and frequency measurement
- PPA – Pulse / Period Accumulate
- SM – Stepper motor

Features

- QOM – Queued Output Match for complex outputs
- UART – Serial interface
- SPI – Synchronous serial interface
- POC – Protected Output Compare
- SPWM – Synchronized Pulse Width Modulation
- GPIO – General purpose I/O (only needed for Puma)

1.3.4.2 Set 2 (Automotive)

- All functions from set 1
- AngleClock - Engine position decoding based on the crank tooth signal
- CamDecode - Engine position synchronization based on the cam signal
- FuelControl - Control the fuel pulse delivery
- SparkControl - Control the spark firing angle and dwell time
- AnglePulse – Output signal based on angle

1.3.4.3 Set 3 (Motor Control 1)

- All functions from set 1
- DC – DC motor with permanent magnet
- DCE – DC motor with separately excited stator windings
- BLDC – Brushless DC motor with Hall sensors
- QD - Quadrature decode function
- HS - Hall sensor signals decode function

1.3.4.4 Set 4 (Motor Control 2)

- All functions from set 1.
- ACIM – 3-phase AC induction motor with V/Hz control
- ACIMVC – 3-phase AC induction motor with vector control
- PMSMVC – 3-phase PM motor with vector control
- PMSMTVC – 3-phase PM motor with torque vector control
- QD - Quadrature decode function
- HS - Hall sensor signals decode function

1.3.5 Debug Module

The ColdFire processor core debug interface is provided to support system debugging in conjunction with low-cost debug and emulator development tools. Through a standard debug interface, users can access real-time trace and debug information. This allows the processor and system to be debugged at full speed without the need for costly in-circuit emulators. The debug interface is a superset of the BDM interface provided on Motorola's 683xx family of parts.

The on-chip breakpoint resources include a total of 6 programmable registers—a set of address registers (with two 32-bit registers), a set of data registers (with a 32-bit data register plus a 32-bit data mask register), and one 32-bit PC register plus a 32-bit PC mask register. These registers can be accessed through the dedicated debug serial communication channel or from the processor's supervisor mode programming model. The breakpoint registers can be configured to generate triggers by combining the address, data, and PC conditions in a variety of single or dual-level definitions. The trigger event can be programmed to generate a processor halt or initiate a debug interrupt exception.

To support program trace, the Version 2 debug module provides processor status (PST[3:0]) and debug data (DDATA[3:0]) ports. These buses and the PSTCLK output provide execution status, captured operand data, and branch target addresses defining processor activity at the CPU's clock rate.

The integration of the eTPU on the MCF523x family marks the first time that ColdFire and Nexus debug subsystems have been present in a single device. The eTPU's Nexus functionality has been merged into the standard ColdFire debug model. This includes access to the eTPU Nexus debug registers via the standard ColdFire BDM serial interface or the processor WDEBUG instruction and run/halt cross triggering capability between eTPU Nexus and ColdFire BDM.

1.3.6 JTAG

The MCF523x supports circuit board test strategies based on the Test Technology Committee of IEEE and the Joint Test Action Group (JTAG). The test logic includes a test access port (TAP) consisting of a 16-state controller, an instruction register, and three test registers (a 1-bit bypass register, a 330-bit boundary-scan register, and a 32-bit ID register). The boundary scan register links the device's pins into one shift register. Test logic, implemented using static logic design, is independent of the device system logic.

The MCF523x implementation can do the following:

- Perform boundary-scan operations to test circuit board electrical continuity
- Sample MCF523x system pins during operation and transparently shift out the result in the boundary scan register
- Bypass the MCF523x for a given circuit board test by effectively reducing the boundary-scan register to a single bit
- Disable the output drive to pins during circuit-board testing
- Drive output pins to stable levels

1.3.7 On-chip Memories

1.3.7.1 Cache

The 8-Kbyte cache can be configured into one of three possible organizations: an 8-Kbyte instruction cache, an 8-Kbyte data cache or a split 4-Kbyte instruction/4-Kbyte data cache. The configuration is software-programmable by control bits within the privileged Cache Configuration Register (CACR). In all configurations, the cache is a direct-mapped single-cycle memory, organized as 512 lines, each containing 16 bytes of data. The memories consist of a 512-entry tag array (containing addresses and control bits) and a 8-Kbyte data array, organized as 2048×32 bits.

If the desired address is mapped into the cache memory, the output of the data array is driven onto the ColdFire core's local data bus, completing the access in a single cycle. If the data is not mapped into the tag memory, a cache miss occurs and the processor core initiates a 16-byte line-sized fetch. The cache module

Features

includes a 16-byte line fill buffer used as temporary storage during miss processing. For all data cache configurations, the memory operates in write-through mode and all operand writes generate an external bus cycle.

1.3.7.2 SRAM

The SRAM module provides a general-purpose 64-Kbyte memory block that the ColdFire core can access in a single cycle. The location of the memory block can be set to any 64-Kbyte boundary within the 4-Gbyte address space. The memory is ideal for storing critical code or data structures, for use as the system stack, or for storing FEC data buffers. Because the SRAM module is physically connected to the processor's high-speed local bus, it can quickly service core-initiated accesses or memory-referencing commands from the debug module.

The SRAM module is also accessible by the DMA and FEC non-core bus masters. The dual-ported nature of the SRAM makes it ideal for implementing applications with double-buffer schemes, where the processor and a DMA device operate in alternate regions of the SRAM to maximize system performance. As an example, system performance can be increased significantly if Ethernet packets are moved from the FEC into the SRAM (rather than external memory) prior to any processing.

1.3.8 Fast Ethernet Controller (FEC)

The MCF523x's integrated Fast Ethernet Controller (FEC) performs the full set of IEEE 802.3/Ethernet CSMA/CD media access control and channel interface functions. The FEC supports connection and functionality for the 10/100 Mbps 802.3 media independent interface (MII). It requires an external transceiver (PHY) to complete the interface to the media.

1.3.9 FlexCAN

There are up to 2 FlexCAN modules on the MCF523x (refer to Table 1). The FlexCAN module is a communication controller implementing the 2.0B CAN protocol. The CAN protocol is commonly used as an industrial control serial data bus, meeting the specific requirements of real-time processing, reliable operation in a harsh EMI environment, cost-effectiveness, and required bandwidth. FlexCAN contains 16 message buffers.

1.3.10 UARTs

The MCF523x contains three full-duplex UARTs that function independently. The three UARTs can be clocked by the system bus clock, eliminating the need for an externally supplied clock. They can use DMA requests on transmit-ready and receive-ready as well as interrupt requests for servicing. Flow control is only available on two of the UARTs.

1.3.11 I²C Bus

The I²C bus is a two-wire, bidirectional serial bus that provides a simple, efficient method of data exchange, minimizing the interconnection between devices. This bus is suitable for applications requiring occasional communications over a short distance between many devices.

1.3.12 QSPI

The queued serial peripheral interface module provides a high-speed synchronous serial peripheral interface with queued transfer capability. It allows up to 16 transfers to be queued at once, eliminating CPU intervention between transfers.

1.3.13 Cryptography

The MCF5235 device incorporates small, fast, dedicated hardware accelerators for random number generation, message digest and hashing, and the DES, 3DES, and AES block cipher functions allowing for the implementation of common Internet security protocol cryptography operations with performance well in excess of software-only algorithms.

1.3.14 DMA Timers (DTIM0-DTIM3)

There are four independent, DMA-transfer-generating 32-bit timers (DTIM[3:0]) on the MCF523x. Each timer module incorporates a 32-bit timer with a separate register set for configuration and control. The timers can be configured to operate from the system clock or from an external clock source using one of the DTINx signals. If the system clock is selected, it can be divided by 16 or 1. The input clock is further divided by a user-programmable 8-bit prescaler which clocks the actual timer counter register (TCRn). Each of these timers can be configured for input capture or reference compare mode. By configuring the internal registers, each timer may be configured to assert an external signal, generate an interrupt on a particular event or cause a DMA transfer.

1.3.15 Periodic Interrupt Timers (PIT0-PIT3)

The four periodic interrupt timers (PIT[3:0]) are 16-bit timers that provide precise interrupts at regular intervals with minimal processor intervention. Each timer can either count down from the value written in its PIT modulus register, or it can be a free-running down-counter.

1.3.16 Software Watchdog Timer

The watchdog timer is a 16-bit timer that facilitates recovery from runaway code. The watchdog counter is a free-running down-counter that generates a reset on underflow. To prevent a reset, software must periodically restart the countdown.

1.3.17 Clock Module and Phase Locked Loop (PLL)

The clock module contains a crystal oscillator (OSC), phase-locked loop (PLL), reduced frequency divider (RFD), status/control registers, and control logic. To improve noise immunity, the PLL and OSC have their own power supply inputs, VDDPLL and VSSPLL. All other circuits are powered by the normal supply pins, VDD and VSS.

1.3.18 Interrupt Controllers (INTC0/INTC1)

There are two interrupt controllers on the MCF523x, each of which can support up to 63 interrupt sources each for a total of 126. Each interrupt controller is organized as 7 levels with 9 interrupt sources per level.

Features

Each interrupt source has a unique interrupt vector, and 56 of the 63 sources of a given controller provide a programmable level [1-7] and priority within the level.

1.3.19 DMA Controller

The Direct Memory Access (DMA) Controller Module provides an efficient way to move blocks of data with minimal processor interaction. The DMA module provides four channels (DMA0-DMA3) that allow byte, word, longword or 16-byte burst line transfers. These transfers are triggered by software explicitly setting a DCRn[START] bit. Other sources include the DMA timer, external sources via the \overline{DREQ} signal, UARTs, and the eTPU. The DMA controller supports single or dual address to off-chip devices or dual address to on-chip devices.

1.3.20 External Bus Interface (EBI)

The external bus interface handles the transfer of information between the core and memory, peripherals, or other processing elements in the external address space. Features have been added to support external Flash modules, for secondary wait states on reads and writes, and a signal to support Active-Low Address Valid (a signal on most Flash memories).

Programmable chip-select outputs provide signals to enable external memory and peripheral circuits, providing all handshaking and timing signals for automatic wait-state insertion and data bus sizing.

Base memory address and block size are programmable, with some restrictions. For example, the starting address must be on a boundary that is a multiple of the block size. Each chip select can be configured to provide read and write enable signals suitable for use with most popular static RAMs and peripherals. Data bus width (8-bit, 16-bit, or 32-bit) is programmable on all chip selects, and further decoding is available for protection from user mode access or read-only access.

1.3.21 SDRAM Controller

The SDRAM controller provides all required signals for glueless interfacing to a variety of JEDEC-compliant SDRAM devices. SD_SRAS/SD_SCAS address multiplexing is software configurable for different page sizes. To maintain refresh capability without conflicting with concurrent accesses on the address and data buses, $\overline{SD_SRAS}$, $\overline{SD_SCAS}$, \overline{SDWE} , $\overline{SD_CS}[1:0]$ and SD_CKE are dedicated SDRAM signals. <<<Is SD_CKE active low?>>>

1.3.22 Reset

The reset controller is provided to determine the cause of reset, assert the appropriate reset signals to the system, and keep track of what caused the last reset. The power management registers for the internal low-voltage detect (LVD) circuit are implemented in the reset module. There are six sources of reset:

- External
- Power-on reset (POR)
- Watchdog timer
- Phase locked-loop (PLL) loss of lock
- PLL loss of clock
- Software

External reset on the $\overline{\text{RSTOUT}}$ pin is software-assertable independent of chip reset state. There are also software-readable status flags indicating the cause of the last reset.

1.3.23 GPIO

Like the MC68332, unused bus interface and peripheral pins on the MCF523x can be used as discrete general-purpose inputs and outputs. These are managed by a dedicated GPIO module that logically groups all pins into ports located within a contiguous block of memory-mapped control registers.

All of the pins associated with the external bus interface may be used for several different functions. Their primary function is to provide an external memory interface to access off-chip resources. When not used for this, all of the pins may be used as general-purpose digital I/O pins. In some cases, the pin function is set by the operating mode, and the alternate pin functions are not supported. The digital I/O pins on the MCF523x are grouped into 8-bit ports. Some ports do not use all eight bits. Each port has registers that configure, monitor, and control the port pins.

2 Signal Descriptions

This section describes signals that connect off chip. It includes a table of signal properties, and detailed discussion of the MCF523x signals.

2.1 Signal Properties

Table 2 lists all of the signals grouped by function. The “Dir” column is the direction for the primary function of the pin.

Table 2. Signal Descriptions

Signal Name	GPIO	Alternate 1	Alternate 2	Qty.	Dir.	Pullup
Reset						
$\overline{\text{RESET}}$	—	—	—	1	I	Pullup
$\overline{\text{RSTOUT}}$	—	—	—	1	O	—
Clock						
EXTAL	—	—	—	1	I	—
XTAL	—	—	—	1	O	—
CLKOUT	—	—	—	1	O	—
Mode Selection						
CLKMOD[1:0]	—	—	—	2	I/O	Pullup
$\overline{\text{RCON}}$	—	—	—	1	I	Pullup
External Memory Interface and Ports						
A[23:21]	PADDR[7:5]	$\overline{\text{CS}}$ [6:4]	—	3	O	—
A[20:0]	—	—	—	21	O	—
D[31:16]	—	—	—	16	I/O	—
D[15:8]	PDATAH[7:0]	—	—	8	I/O	—

Table 2. Signal Descriptions (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Qty.	Dir.	Pullup
D[7:0]	PDATA[7:0]	—	—	8	I/O	—
$\overline{\text{BS}}[3:0]$	PBS[7:4]	$\overline{\text{CAS}}[3:0]$	—	4	O	—
$\overline{\text{OE}}$	PBUSCTL7	—	—	1	O	—
$\overline{\text{TA}}$	PBUSCTL6	—	—	1	I	Pullup
$\overline{\text{TEA}}$	PBUSCTL5	$\overline{\text{DREQ}}1$	—	1	I	Pullup
$\overline{\text{R/W}}$	PBUSCTL4	—	—	1	I/O	Pullup
TSIZ1	PBUSCTL3	$\overline{\text{DACK}}1$	—	1	O	Pullup
TSIZ0	PBUSCTL2	$\overline{\text{DACK}}0$	—	1	O	Pullup
$\overline{\text{TIP}}$	PBUSCTL0	$\overline{\text{DREQ}}0$	—	1	O	Pullup
$\overline{\text{TS}}$	PBUSCTL1	$\overline{\text{DACK}}2$	—	1	O	Pullup
Chip Selects						
$\overline{\text{CS}}[7:4]$	PCS[7:4]	—	—	2	O	Pullup
$\overline{\text{CS}}[3:2]$	PCS[3:2]	$\overline{\text{SD_CS}}[1:0]$	—	2	O	—
$\overline{\text{CS}}1$	PCS1	—	—	1	O	—
$\overline{\text{CS}}0$	—	—	—	1	O	—
SDRAM Controller						
$\overline{\text{SD_RAS}}$	PSDRAM3	—	—	1	O	—
$\overline{\text{SD_CAS}}$	PSDRAM4	—	—	1	O	—
$\overline{\text{SD_WE}}$	PSDRAM5	—	—	1	O	—
$\overline{\text{SD_CS}}[1:0]$	PSDRAM[1:0]	—	—	1	O	Pullup
$\overline{\text{SD_CKE}}$	PSDRAM2	—	—	1	O	Pullup
External Interrupts Port						
$\overline{\text{IRQ}}[7:3]$	PIRQ[7:3]	—	—	5	I	Pullup
$\overline{\text{IRQ}}2$	PIRQ2	$\overline{\text{DREQ}}2$	—	1	I	Pullup
$\overline{\text{IRQ}}1$	PIRQ1	—	—	1	I	Pullup
eTPU						
TPUCH31	—	ECOL	—	1	I/O	—
TPUCH30	—	ECRS	—	1	I/O	—
TPUCH29	—	ERXCLK	—	1	I/O	—
TPUCH28	—	ERXDV	—	1	I/O	—
TPUCH[27:24]	—	ERXD[3:0]	—	4	I/O	—
TPUCH23	—	ERXER	—	1	I/O	—
TPUCH22	—	ETXCLK	—	1	I/O	—
TPUCH21	—	ETXEN	—	1	I/O	—

Table 2. Signal Descriptions (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Qty.	Dir.	Pullup
TPUCH20	—	ETXER	—	1	I/O	—
TPUCH[19:16]	—	ETXD[3:0]	—	4	I/O	—
TPUCH15	—	ECOL	—	1	I/O	—
TPUCH14	—	ECRS	—	1	I/O	—
TPUCH13	—	ERXCLK	—	1	I/O	—
TPUCH12	—	ERXDV	—	1	I/O	—
TPUCH[11:8]	—	ERXD[3:0]	—	4	I/O	—
TPUCH7	—	ERXER	—	1	I/O	—
TPUCH6	—	ETXCLK	—	1	I/O	—
TPUCH5	—	ETXEN	—	1	I/O	—
TPUCH4	—	ETXER	—	1	I/O	—
TPUCH[3:0]	—	ETXD[3:0]	—	4	I/O	—
LTPUODIS	PETPU0	—	—	1	I/O	Pullup
TCRCLK	PETPU2	—	—	1	I/O	Pullup
UTPUODIS	PETPU1	—	—	1	I/O	Pullup
FEC						
EMDIO	PFECI2C2	I2C_SDA	U2RXD	1	I/O	—
EMDC	PFECI2C3	I2C_SCL	U2TXD	1	O	—
ECOL	—	—	—	1	I	—
ECRS	—	—	—	1	I	—
ERXCLK	—	—	—	1	I	—
ERXDV	—	—	—	1	I	—
ERXD[3:0]	—	—	—	4	I	—
ERXER	—	—	—	1	I	—
ETXCLK	—	—	—	1	I	—
ETXEN	—	—	—	1	O	—
ETXER	—	—	—	1	O	—
ETXD[3:0]	—	—	—	4	O	—
Feature Control						
eTPU/EthENB	—	—	—	1	I	Pulldown
I²C						
I2C_SDA	PFECI2C1	CAN0RX	—	1	I/O	Pullup
I2C_SCL	PFECI2C0	CAN0TX	—	1	I/O	Pullup

Table 2. Signal Descriptions (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Qty.	Dir.	Pullup
QSPI						
QSPI_CS1	PQSPI4	SD_CKE	—	1	O	—
QSPI_CS0	PQSPI3	—	—	1	O	—
QSPI_CLK	PQSPI2	I2C_SCL	—	1	O	—
QSPI_DIN	PQSPI1	I2C_SDA	—	1	I	—
QSPI_DOUT	PQSPI0	—	—	1	O	—
UARTs						
U2RXD	PUARTH0	CAN1RX	—	1	I	Pullup
U2TXD	PUARTH1	CAN1TX	—	1	O	—
U1RXD	PUARTL4	CAN0RX	—	1	I	—
U1TXD	PUARTL5	CAN0TX	—	1	O	—
U0RXD	PUARTL0	—	—	1	I	—
U0TXD	PUARTL1	—	—	1	O	—
$\overline{U1CTS}$	PUARTL7	$\overline{U2CTS}$	—	1	I	—
$\overline{U1RTS}$	PUARTL6	$\overline{U2RTS}$	—	1	O	—
$\overline{U0CTS}$	PUARTL3	—	—	1	I	—
$\overline{U0RTS}$	PUARTL2	—	—	1	O	—
DMA Timers						
DTIN3	PTIMER7	$\overline{U2CTS}$	—	1	I	—
DTOUT3	PTIMER6	$\overline{U2RTS}$	—	1	O	—
DTIN2	PTIMER5	$\overline{DREQ2}$	DTOUT2	1	I	—
DTOUT2	PTIMER4	$\overline{DREQ2}$	—	1	O	—
DTIN1	PTIMER3	$\overline{DREQ1}$	DTOUT1	1	I	—
DTOUT1	PTIMER2	$\overline{DACK1}$	—	1	O	—
DTIN0	PTIMER1	$\overline{DREQ0}$	—	1	I	—
DTOUT0	PTIMER0	$\overline{DACK0}$	—	1	O	—
Debug and JTAG Test Port Control						
\overline{TRST}	—	DSCLK	—	1	I	Pullup
TCLK	—	PSTCLK	—	1	I	Pullup
TMS	—	\overline{BKPT}	—	1	I	Pullup
TDI	—	DSI	—	1	I	Pullup
TDO	—	DSO	—	1	O	—
JTAG_EN	—	—	—	1	I	Pullup
DDATA[3:0]	—	—	—	4	O	Pullup

Table 2. Signal Descriptions (continued)

Signal Name	GPIO	Alternate 1	Alternate 2	Qty.	Dir.	Pullup
PST[3:0]	—	—	—	4	O	—
Test						
TEST	—	—	—	1	I	—
PLL_TEST	—	—	—	1	I	—
Power Supplies						
VDDPLL	—	—	—	1	I	—
VSSPLL	—	—	—	1	I	—
OVDD	—	—	—	22	I	—
OVSS	—	—	—	22	I	—
VDD	—	—	—	4	I	—
VSS	—	—	—	4	I	—

2.2 Signal Primary Functions

2.2.1 Reset Signals

Table 3 describes signals that are used to either reset the chip or as a reset indication.

Table 3. Reset Signals

Signal Name	Abbreviation	Function	I/O
Reset In	$\overline{\text{RESET}}$	Primary reset input to the device. Asserting $\overline{\text{RESET}}$ immediately resets the CPU and peripherals.	I
Reset Out	$\overline{\text{RSTOUT}}$	Driven low for 128 CPU clocks when the soft reset bit of the system configuration register (SCR[SOFTRST]) is set. It is driven low for 32K CPU clocks when the software watchdog timer times out or when a low input level is applied to $\overline{\text{RESET}}$.	O

2.2.2 PLL and Clock Signals

Table 4 describes signals that are used to support the on-chip clock generation circuitry.

Table 4. PLL and Clock Signals

Signal Name	Abbreviation	Function	I/O
External Clock In	EXTAL	Always driven by an external clock input except when used as a connection to the external crystal when the internal oscillator circuit is used. The clock source is configured during reset by CLKMOD[1:0].	I
Crystal	XTAL	Used as a connection to the external crystal when the internal oscillator circuit is used to drive the crystal.	O
Clock Out	CLKOUT	This output signal reflects the internal system clock.	O

2.2.3 Mode Selection

Table 5 describes signals used in mode selection.

Table 5. Mode Selection Signals

Signal Name	Abbreviation	Function	I/O
Clock Mode Selection	CLKMOD[1:0]	Configure the clock mode after reset.	I
Reset Configuration	RCON	Indicates whether the external D[31:16] pin states affect chip configuration at reset.	I

2.2.4 External Memory Interface Signals

Table 6 describes signals that are used for doing transactions on the external bus.

Table 6. External Memory Interface Signals

Signal Name	Abbreviation	Function	I/O
Address Bus	A[23:0]	The 24 dedicated address signals define the address of external byte, word, and longword accesses. These three-state outputs are the 24 lsb's of the internal 32-bit address bus and multiplexed with the SDRAM controller row and column addresses. Unused pins are can be configured as GPIO. The A[23:21] pins can also be configured as CS[6:4].	O
Data Bus	D[31:0]	These three-state bidirectional signals provide the general purpose data path between the processor and all other devices. The D[15:0] pins can be configured as GPIO when using a 16-bit bus.	I/O
Byte Strobes	BS[3:0]	Define the flow of data on the data bus. During SRAM and peripheral accesses, these output signals indicate that data is to be latched or driven onto a byte of the data when driven low. The BS[3:0] signals are asserted only to the memory bytes used during a read or write access. BS0 controls access to the most significant byte lane of data, and BS3 controls access to the least significant byte lane of data. The BS[3:0] signals are asserted during accesses to on-chip peripherals but not to on-chip SRAM, or cache. During SDRAM accesses, these signals act as the CAS[3:0] signals, which indicate a byte transfers between SDRAM and the chip when driven high. For SRAM or Flash devices, the BS[3:0] outputs should be connected to individual byte strobe signals. For SDRAM devices, the BS[3:0] should be connected to individual SDRAM DQM signals. Note that most SDRAMs associate DQM3 with the MSB, in which case BS0 should be connected to the SDRAM's DQM3 input. These pins can also be configured as GPIO.	O
Output Enable	OE	Indicates when an external device can drive data during external read cycles. This pin can also be configured as GPIO.	O

Table 6. External Memory Interface Signals (continued)

Signal Name	Abbreviation	Function	I/O
Transfer Acknowledge	$\overline{\text{TA}}$	Indicates that the external data transfer is complete. During a read cycle, when the processor recognizes $\overline{\text{TA}}$, it latches the data and then terminates the bus cycle. During a write cycle, when the processor recognizes $\overline{\text{TA}}$, the bus cycle is terminated. This pin can also be configured as GPIO.	I
Transfer Error Acknowledge	$\overline{\text{TEA}}$	Indicates an error condition exists for the bus transfer. The bus cycle is terminated and the CPU begins execution of the access error exception. This pin can also be configured as GPIO or DMA transfer request signal $\overline{\text{DREQ0}}$.	I
Read/Write	$\text{R}/\overline{\text{W}}$	Indicates the direction of the data transfer on the bus for SRAM ($\text{R}/\overline{\text{W}}$) and SDRAM ($\overline{\text{SD_WE}}$) accesses. A logic 1 indicates a read from a slave device and a logic 0 indicates a write to a slave device. This pin can also be configured as GPIO.	O
Transfer Size	$\overline{\text{TSIZ}}[1:0]$	When the device is in normal mode, dynamic bus sizing lets the programmer change data bus width between 8, 16, and 32 bits for each chip select. The initial width for the bootstrap program chip select, CS0 , is determined by the state of $\overline{\text{TSIZ}}[1:0]$. The program should select bus widths for the other chip selects before accessing the associated memory space. These pins are output pins. These pins can also be configured as GPIO or DMA transfer acknowledge signals $\overline{\text{DACK1}}/\overline{\text{DACK0}}$.	O
Transfer Start	$\overline{\text{TS}}$	Bus control output signal indicating the start of a transfer. This pin can also be configured as GPIO or DMA transfer acknowledge signal $\overline{\text{DACK2}}$.	O
Transfer in Progress	$\overline{\text{TIP}}$	Bus control output signal indicating bus transfer in progress. This pin can also be configured as GPIO or DMA transfer request signal $\overline{\text{DREQ0}}$.	O
Chip Selects	$\overline{\text{CS}}[7:0]$	These output signals select external devices for external bus transactions. The $\overline{\text{CS}}[3:2]$ can also be configured to function as SDRAM chip selects $\overline{\text{SD_CS}}[1:0]$. $\overline{\text{CS}}[7:1]$ pins can also be configured as GPIO.	O

2.2.5 SDRAM Controller Signals

Table 7 describes signals that are used for SDRAM accesses.

Table 7. SDRAM Controller Signals

Signal Name	Abbreviation	Function	I/O
SDRAM Synchronous Row Address Strobe	$\overline{\text{SD_SRAS}}$	SDRAM synchronous row address strobe. This pin is configured as GPIO.	O
SDRAM Synchronous Column Address Strobe	$\overline{\text{SD_SCAS}}$	SDRAM synchronous column address strobe. This pin is configured as GPIO.	O
SDRAM Write Enable	$\overline{\text{SD_WE}}$	SDRAM write enable. This pin is configured as GPIO.	O
SDRAM Chip Selects	$\overline{\text{SD_CS}}[1:0]$	SDRAM chip select signals. These pints are configured as GPIO.	O
SDRAM Clock Enable	$\overline{\text{SD_CKE}}$	SDRAM clock enable. This pin is configured as GPIO.	O

2.2.6 External Interrupt Signals

Table 8 describes the external interrupt signals.

Table 8. External Interrupt Signals

Signal Name	Abbreviation	Function	I/O
External Interrupts	$\overline{\text{IRQ}}[7:1]$	External interrupt sources. $\overline{\text{IRQ2}}$ can also be configured as DMA request signal DREQ2. These pins are configured as GPIO.	I

2.2.7 eTPU

Table 9 describes eTPU signals.

Table 9. eTPU Signals

Signal Name	Abbreviation	Function	I/O
TCRCLK	TCRCLK	Used to clock the TCR1/2 counters or gate the TCR2 clock.	I
TPUCH[31:0]	TPUCH[31:0]	Channel pins for the eTPU module. They can also be configured for Ethernet controller functionality. See table Table 2 and Section 2.2.8, "Ethernet Module (FEC) Signals," for details.	I/O
LTPUODIS	LTPUODIS	Disables eTPU outputs on the lower 16 channels of the eTPU.	I/O
UTPUDIS	UTPUDIS	Disables eTPU outputs on the upper 16 channels of the eTPU.	I/O

2.2.8 Ethernet Module (FEC) Signals

The following signals are used by the Ethernet module for data and clock signals. Some of these signals are muxed with eTPU channels on the MCF5235 and dedicated on the other members of the family that have an Ethernet Module.

Table 10. Ethernet Module (FEC) Signals

Signal Name	Abbreviation	Function	I/O
Management Data	EMDIO	Transfers control information between the external PHY and the media-access controller. Data is synchronous to EMDC. Applies to MII mode operation. This signal is an input after reset. When the FEC is operated in 10Mbps 7-wire interface mode, this signal should be connected to VSS. This pin can also be configured as GPIO port AS5 or UART2 receive data U2RXD.	I/O
Management Data Clock	EMDC	In Ethernet mode, EMDC is an output clock which provides a timing reference to the PHY for data transfers on the EMDIO signal. Applies to MII mode operation. This pin can also be configured as UART2 transmit data U2TXD or I ² C clock I2C_SCL.	O
Transmit Clock	ETXCLK	Input clock which provides a timing reference for ETXEN, ETXD[3:0] and ETXER	I
Transmit Enable	ETXEN	Indicates when valid nibbles are present on the MII. This signal is asserted with the first nibble of a preamble and is negated before the first ETXCLK following the final nibble of the frame.	O
Transmit Data 0	ETXD0	ETXD0 is the serial output Ethernet data and is only valid during the assertion of ETXEN. This signal is used for 10-Mbps Ethernet data. It is also used for MII mode data in conjunction with ETXD[3:1].	O
Collision	ECOL	Asserted upon detection of a collision and remains asserted while the collision persists. This signal is not defined for full-duplex mode.	I
Receive Clock	ERXCLK	Provides a timing reference for ERXDV, ERXD[3:0], and ERXER.	I
Receive Data Valid	ERXDV	Asserting the receive data valid (ERXDV) input indicates that the PHY has valid nibbles present on the MII. ERXDV should remain asserted from the first recovered nibble of the frame through to the last nibble. Assertion of ERXDV must start no later than the SFD and exclude any EOF.	I
Receive Data 0	ERXD0	ERXD0 is the Ethernet input data transferred from the PHY to the media-access controller when ERxDV is asserted. This signal is used for 10-Mbps Ethernet data. This signal is also used for MII mode Ethernet data in conjunction with ERXD[3:1].	I
Carrier Receive Sense	ECRS	When asserted, indicates that transmit or receive medium is not idle. Applies to MII mode operation. This pin can also be configured and UART2 receive U2RXD or I2C data I2C_SDA.	I

Signal Primary Functions

Table 10. Ethernet Module (FEC) Signals (continued)

Signal Name	Abbreviation	Function	I/O
Transmit Data 1–3	ETXD[3:1]	In Ethernet mode, these pins contain the serial output Ethernet data and are valid only during assertion of ETXEN in MII mode.	O
Transmit Error	ETXER	In Ethernet mode, when ETXER is asserted for one or more clock cycles while ETXEN is also asserted, the PHY sends one or more illegal symbols. ETXER has no effect at 10 Mbps or when ETXEN is negated. Applies to MII mode operation.	O
Receive Data 1–3	ERXD[3:1]	In Ethernet mode, these pins contain the Ethernet input data transferred from the PHY to the Media Access Controller when ERXDV is asserted in MII mode operation.	I
Receive Error	ERXER	In Ethernet mode, ERXER—when asserted with ERXDV—indicates that the PHY has detected an error in the current frame. When ERXDV is not asserted ERXER has no effect. Applies to MII mode operation.	O

2.2.9 Feature Control

The eTPU/ $\overline{\text{EthENB}}$ signal configures which modules are available to the user. This input signal selects the muxing of the eTPU and Ethernet controller.

2.2.10 I²C I/O Signals

Table 11 describes the I²C serial interface module signals.

Table 11. I²C I/O Signals

Signal Name	Abbreviation	Function	I/O
Serial Clock	I2C_SCL	Open-drain clock signal for the for the I ² C interface. Either it is driven by the I ² C module when the bus is in the master mode or it becomes the clock input when the I ² C is in the slave mode. This pin can also be configured as GPIO or as UART2 transmit signal U2TXD.	I/O
Serial Data	I2C_SDA	Open-drain signal that serves as the data input/output for the I ² C interface.	I/O

2.2.11 Queued Serial Peripheral Interface (QSPI)

Table 12 describes QSPI signals.

Table 12. Queued Serial Peripheral Interface (QSPI) Signals

Signal Name	Abbreviation	Function	I/O
QSPI Synchronous Serial Output	QSPI_DOUT	Provides the serial data from the QSPI and can be programmed to be driven on the rising or falling edge of QSPI_CLK. Each byte is sent msb first. This pin can also be configured as GPIO.	O
QSPI Synchronous Serial Data Input	QSPI_DIN	Provides the serial data to the QSPI and can be programmed to be sampled on the rising or falling edge of QSPI_CLK. Each byte is written to RAM lsb first. This pin can also be configured as GPIO or as I ² C data signal I2C_SDA.	I
QSPI Serial Clock	QSPI_CLK	Provides the serial clock from the QSPI. The polarity and phase of QSPI_CLK are programmable. The output frequency is programmed according to the following formula, in which <i>n</i> can be any value between 1 and 255: $\text{SPI_CLK} = f_{\text{sys}}/2 \div n$ This pin can also be configured as GPIO or as I2C clock signal I2C_SCL.	O
Synchronous Peripheral Chip Selects	QSPI_CS[1:0]	Provide QSPI peripheral chip selects that can be programmed to be active high or low. QSPI_CS1 can also be configured as SDRAM clock enable signal SD_CKE. These pins can also be configured as GPIO.	O

2.2.12 UART Module Signals

The UART modules use the signals in this section for data. The baud rate clock inputs are not supported.

Table 13. UART Module Signals

Signal Name	Abbreviation	Function	I/O
Transmit Serial Data Output	U2TXD/U1TXD /U0TXD	Transmitter serial data outputs for the UART modules. The output is held high (mark condition) when the transmitter is disabled, idle, or in the local loopback mode. Data is shifted out, lsb first, on this pin at the falling edge of the serial clock source. U1TXD can also be configured as Controller Area Network Transmit data output CAN0TX. U2TXD can also be configured as Controller Area Network Transmit data output CAN1TX. All pins can also be configured as GPIO.	O

Table 13. UART Module Signals (continued)

Signal Name	Abbreviation	Function	I/O
Receive Serial Data Input	U2RXD/U1RXD/U0RXD	Receiver serial data inputs for the UART modules. Data received on this pin is sampled on the rising edge of the serial clock source lsb first. When the UART clock is stopped for power-down mode, any transition on this pin restarts it. U1RXD can also be configured as Controller Area Network Transmit data input CAN0RX. U2RXD can also be configured as Controller Area Network Transmit data output CAN1RX. All pins can also be configured as GPIO.	I
Clear-to-Send	$\overline{U1CTS/U0CTS}$	Indicate to the UART modules that they can begin data transmission.	I
Request-to-Send	$\overline{U1RTS/U0RTS}$	Automatic request-to-send outputs from the UART modules. $\overline{U1RTS/U0RTS}$ can also be configured to be asserted and negated as a function of the RxFIFO level.	O

2.2.13 DMA Timer Signals

Table 14 describes the signals of the four DMA timer modules.

Table 14. DMA Timer Signals

Signal Name	Abbreviation	Function	I/O
DMA Timer 0 Input	DTIN0	Can be programmed to cause events to occur in first platform timer. It can either clock the event counter or provide a trigger to the timer value capture logic. This pin can also be configured as DMA request line signal, $\overline{DREQ0}$, or as GPIO.	I
DMA Timer 0 Output	DTOUT0	The output from first platform timer. This pin can also be configured as DMA acknowledge signal, $\overline{DACK0}$, or as GPIO.	O
DMA Timer 1 Input	DTIN1	Can be programmed to cause events to occur in the second platform timer. This can either clock the event counter or provide a trigger to the timer value capture logic. This pin can also be configured as DMA request line signal, $\overline{DREQ1}$, or as GPIO.	I
DMA Timer 1 Output	DTOUT1	The output from the second platform timer. This pin can also be configured as DMA acknowledge signal, $\overline{DACK1}$, or as GPIO.	O

Table 14. DMA Timer Signals (continued)

Signal Name	Abbreviation	Function	I/O
DMA Timer 2 Input	DTIN2	Can be programmed to cause events to occur in the third platform timer. It can either clock the event counter or provide a trigger to the timer value capture logic. This pin can also be configured as DMA request line signal, $\overline{DREQ2}$, or as GPIO.	I
DMA Timer 2 Output	DTOUT2	The output from the third platform timer. This pin can also be configured as GPIO.	I
DMA Timer 3 Input	DTIN3	Can be programmed as an input that causes events to occur in the fourth platform timer. This can either clock the event counter or provide a trigger to the timer value capture logic. This pin can also be configured as QSPI chip select 2 signal, UART 2 clear-to-send signal, $\overline{U2CTS}$, or as GPIO.	I
DMA Timer 3 Output	DTOUT3	The output from the fourth platform timer. This pin can also be configured as QSPI chip select 2 signal, UART 2 request-to-send signal, $\overline{U2RTS}$, or as GPIO.	O

2.2.14 Debug Support Signals

These signals are used as the interface to the on-chip JTAG controller and also to interface to the BDM logic.

Table 15. Debug Support Signals

Signal Name	Abbreviation	Function	I/O
Test Reset	\overline{TRST}	This active-low signal is used to initialize the JTAG logic asynchronously.	I
Test Clock	TCLK	Used to synchronize the JTAG logic.	I
Test Mode Select	TMS	Used to sequence the JTAG state machine. TMS is sampled on the rising edge of TCLK.	I
Test Data Input	TDI	Serial input for test instructions and data. TDI is sampled on the rising edge of TCLK.	I
Test Data Output	TDO	Serial output for test instructions and data. TDO is three-stateable and is actively driven in the shift-IR and shift-DR controller states. TDO changes on the falling edge of TCLK.	O
Development Serial Clock	DSCLK	Clocks the serial communication port to the BDM module during packet transfers.	I
Breakpoint	\overline{BKPT}	Used to request a manual breakpoint.	I

Signal Primary Functions

Table 15. Debug Support Signals (continued)

Signal Name	Abbreviation	Function	I/O
Development Serial Input	DSI	This internally-synchronized signal provides data input for the serial communication port to the BDM module.	I
Development Serial Output	DSO	This internally-registered signal provides serial output communication for BDM module responses.	O
Debug Data	DDATA[3:0]	Display captured processor data and breakpoint status. The CLKOUT signal can be used by the development system to know when to sample DDATA[3:0].	O
Processor Status Outputs	PST[3:0]	Indicate core status, as shown in Table 16. Debug mode timing is synchronous with the processor clock; status is unrelated to the current bus transfer. The CLKOUT signal can be used by the development system to know when to sample PST[3:0].	O

Table 16. Processor Status

PST[3:0]	Processor Status
0000	Continue execution
0001	Begin execution of one instruction
0010	Reserved
0011	Entry into user mode
0100	Begin execution of PULSE and WDDATA instructions
0101	Begin execution of taken branch
0110	Reserved
0111	Begin execution of RTE instruction
1000	Begin one-byte transfer on DDATA
1001	Begin two-byte transfer on DDATA
1010	Begin three-byte transfer on DDATA
1011	Begin four-byte transfer on DDATA
1100	Exception processing
1101	Reserved
1110	Processor is stopped
1111	Processor is halted

2.2.15 Test Signals

Table 17 describes test signals.

Table 17. Test Signals

Signal Name	Abbreviation	Function	I/O
Test	TEST	Reserved for factory testing only and in normal modes of operation should be connected to VSS to prevent unintentional activation of test functions.	I
PLL Test	PLL_TEST	Reserved for factory testing only and should be treated as a no-connect (NC).	I

2.2.16 Power and Ground Pins

The pins described in Table 18 provide system power and ground to the chip. Multiple pins are provided for adequate current capability. All power supply pins must have adequate bypass capacitance for high-frequency noise suppression.

Table 18. Power and Ground Pins

Signal Name	Abbreviation	Function	I/O
PLL Analog Supply	VDDPLL, VSSPLL	Dedicated power supply signals to isolate the sensitive PLL analog circuitry from the normal levels of noise present on the digital power supply.	I
Positive Supply	VDDO	These pins supply positive power to the I/O pads.	I
Positive Supply	VDD	These pins supply positive power to the core logic.	I
Ground	VSS	This pin is the negative supply (ground) to the chip.	

3 Modes of Operation

3.1 Chip Configuration Mode—Device Operating Options

- Chip operating mode:
 - Master mode
- Boot device/size:
 - External device boot
 - 32-bit
 - 16-bit (Default)
 - 8-bit
- Output pad strength:
 - Partial drive strength (Default)
 - Full drive strength

Chip Configuration Mode—Device Operating Options

- Clock mode:
 - Normal PLL with external crystal
 - Normal PLL with external clock
 - 1:1 PLL Mode
 - External oscillator mode (no PLL)
- Chip Select Configuration:
 - PADDR[7:5] configured as chip select(s) and/or address line(s)
 - PADDR[7:5] configured as A23-A21 (default)
 - PADDR configured as $\overline{CS6}$, PADDR[6:5] as A22-A21
 - PADDR[7:6] configured as $\overline{CS}[6:5]$, PADDR5 as A21
 - PADDR[7:5] configured as $\overline{CS}[6:4]$

3.1.1 Chip Configuration Pins

Table 19. Configuration Pin Descriptions

Pin	Chip Configuration Function	Pin State/Meaning	Comments
\overline{RCON}	Chip configuration enable	1 Disabled 0 Enabled	Active low: if asserted, then all configuration pins must be driven appropriately for desired operation
D26, D17, D16	Select chip operating mode	111 Master 110 Reserved 101 Reserved 100 Reserved 0xx Reserved	
D19, D18	Select external boot device data port size	00,11 External (32-bit) 10 External (8-bit) 01 External (16-bit)	Value read defaults to 32-bit
D21	Select output pad drive strength	1 Full 0 Partial	
CLKMOD1, CLKMOD0	Select clock mode	00 External clock mode (no PLL) 01 1:1 PLL mode 10 Normal PLL with external clock reference 11 Normal PLL with crystal clock reference	VDDPLL must be supplied if a PLL mode is selected

Table 19. Configuration Pin Descriptions (continued)

Pin	Chip Configuration Function	Pin State/Meaning	Comments
D25, D24	Select chip select / address line	00 PADDR[7:5] configured as A23-A21 (default) 10 PADDR7 configured as $\overline{CS6}$, PADDR[6:5] as A22-A21 01 PADDR[7:6] configured as $\overline{CS[6:5]}$, PADDR5 as A21 11 PADDR[7:5] configured as $\overline{CS[6:4]}$	
JTAG_EN	Selects BDM or JTAG mode	0 BDM mode 1 JTAG mode	

3.2 Low Power Modes

The following features are available to support applications which require low power.

- Four modes of operation:
 - RUN
 - WAIT
 - DOZE
 - STOP
- Ability to shut down most peripherals independently.
- Ability to shut down the external CLKOUT pin.

There are four modes of operation: RUN, WAIT, DOZE, and STOP. The system enters a low power mode when the user programs the low power bits (LPMD) in the LPCR (Low Power Control Register) in the CIM before the CPU core executes a STOP instruction. This idles the CPU with no cycles active. The LPMD bits indicate to the system and clock controller to power down and stop the clocks appropriately. During STOP mode, the system clock is stopped low.

A wakeup event is required to exit a low power mode and return back to RUN mode. Wakeup events consist of any of the following conditions. See the following sections for more details.

1. Any type of reset.
2. Assertion of the \overline{BKPT} pin to request entry into Debug mode.
3. Debug request bit in the BDM control register to request entry into debug mode.
4. Any valid interrupt request.

3.2.1 RUN Mode

RUN mode is the normal system operating mode. Current consumption in this mode is related directly to the frequency chosen for the system clock.

3.2.2 WAIT Mode

WAIT mode is intended to be used to stop only the CPU core and memory clocks until a wakeup event is detected. In this mode, peripherals may be programmed to continue operating and can generate interrupts, which cause the CPU core to exit from WAIT mode.

3.2.3 DOZE Mode

DOZE mode affects the CPU core in the same manner as WAIT mode, but with a different code on the CIM LPMD bits, which are monitored by the peripherals. Each peripheral defines individual operational characteristics in DOZE mode. Peripherals which continue to run and have the capability of producing interrupts may cause the CPU to exit the DOZE mode and return to the RUN mode. Peripherals which are stopped will restart operation on exit from DOZE mode as defined for each peripheral.

3.2.4 STOP Mode

STOP mode affects the CPU core in the same manner as the WAIT and DOZE modes, but with a different code on the CCM LPMD bits. In this mode, all clocks to the system are stopped and the peripherals cease operation.

STOP mode must be entered in a controlled manner to ensure that any current operation is properly terminated. When exiting STOP mode, most peripherals retain their pre-stop status and resume operation.

3.2.5 Peripheral Shut Down

Most peripherals may be disabled by software in order to cease internal clock generation and remain in a static state. Each peripheral has its own specific disabling sequence (refer to each peripheral description for further details). A peripheral may be disabled at anytime and will remain disabled during any low power mode of operation.

4 Design Recommendations

4.1 Layout

- Use a 4-layer printed circuit board with the VDD and GND pins connected directly to the power and ground planes for the MCF523x.
- See application note AN1259 System Design and Layout Techniques for Noise Reduction in processor-Based Systems.
- Match the PC layout trace width and routing to match trace length to operating frequency and board impedance. Add termination (series or therein) to the traces to dampen reflections. Increase the PCB impedance (if possible) keeping the trace lengths balanced and short. Then do cross-talk analysis to separate traces with significant parallelism or are otherwise "noisy". Use 6 mils trace and separation. Clocks get extra separation and more precise balancing.

4.2 Power Supply

- 33 μF , .1 μF and .01 μF across each power supply

4.3 Decoupling

- Place the decoupling caps as close to the pins as possible, but they can be outside the footprint of the package.
- .1 μF and .01 μF at each supply input

4.4 Buffering

- Use bus buffers on all data/address lines for all off-board accesses and for all on-board accesses when excessive loading is expected. See Section 6, “Preliminary Electrical Characteristics.”

4.5 Pull-up Recommendations

- Use external pull-up resistors on unused inputs. See pin table.

4.6 Clocking Recommendations

- Use a multi-layer board with a separate ground plane.
- Place the crystal and all other associated components as close to the EXTAL and XTAL (oscillator pins) as possible.
- Do not run a high frequency trace around crystal circuit.
- Ensure that the ground for the bypass capacitors is connected to a solid ground trace.
- Tie the ground trace to the ground pin nearest EXTAL and XTAL. This prevents large loop currents in the vicinity of the crystal.
- Tie the ground pin to the most solid ground in the system.
- Do not connect the trace that connects the oscillator and the ground plane to any other circuit element. This tends to make the oscillator unstable.
- Tie XTAL to ground when an external oscillator is clocking the device.

4.7 Interface Recommendations

4.7.1 SDRAM Controller

4.7.1.1 SDRAM Controller Signals in Synchronous Mode

Table 20 shows the behavior of SDRAM signals in synchronous mode.

Table 20. Synchronous DRAM Signal Connections

Signal	Description
$\overline{\text{SD_RAS}}$	Synchronous row address strobe. Indicates a valid SDRAM row address is present and can be latched by the SDRAM. $\overline{\text{SD_RAS}}$ should be connected to the corresponding SDRAM $\overline{\text{SD_RAS}}$. Do not confuse $\overline{\text{SD_RAS}}$ with the DRAM controller's $\overline{\text{SD_CS}}[1:0]$, which should not be interfaced to the SDRAM $\overline{\text{SD_RAS}}$ signals.
$\overline{\text{SD_CAS}}$	Synchronous column address strobe. Indicates a valid column address is present and can be latched by the SDRAM. $\overline{\text{SD_CAS}}$ should be connected to the corresponding signal labeled $\overline{\text{SD_CAS}}$ on the SDRAM.
$\overline{\text{DRAMW}}$	DRAM read/write. Asserted for write operations and negated for read operations.
$\overline{\text{SD_CS}}[1:0]$	Row address strobe. Select each memory block of SDRAMs connected to the MCF523x. One $\overline{\text{SD_CS}}$ signal selects one SDRAM block and connects to the corresponding $\overline{\text{CS}}$ signals.
$\overline{\text{SD_CKE}}$	Synchronous DRAM clock enable. Connected directly to the CKE (clock enable) signal of SDRAMs. Enables and disables the clock internal to SDRAM. When CKE is low, memory can enter a power-down mode where operations are suspended or they can enter self-refresh mode. $\overline{\text{SD_CKE}}$ functionality is controlled by DCR[COC]. For designs using external multiplexing, setting COC allows $\overline{\text{SD_CKE}}$ to provide command-bit functionality.
$\overline{\text{BS}}[3:0]$	Column address strobe. For synchronous operation, $\overline{\text{BS}}[3:0]$ function as byte enables to the SDRAMs. They connect to the DQM signals (or mask qualifiers) of the SDRAMs.
CLKOUT	Bus clock output. Connects to the CLK input of SDRAMs.

4.7.1.2 Address Multiplexing

Table 21 shows the generic address multiplexing scheme for SDRAM configurations. All possible address connection configurations can be derived from this table.

Table 21. Generic Address Multiplexing Scheme

Address Pin	Row Address	Column Address	Notes Related to Port Sizes
17	17	0	8-bit port only
16	16	1	8- and 16-bit ports only
15	15	2	
14	14	3	
13	13	4	
12	12	5	
11	11	6	
10	10	7	
9	9	8	
17	17	16	32-bit port only
18	18	17	16-bit port only or 32-bit port with only 8 column address lines
19	19	18	16-bit port only when at least 9 column address lines are used

Table 21. Generic Address Multiplexing Scheme (continued)

Address Pin	Row Address	Column Address	Notes Related to Port Sizes
20	20	19	
21	21	20	
22	22	21	
23	23	22	
24	24	23	
25	25	24	

The following tables provide a more comprehensive, step-by-step way to determine the correct address line connections for interfacing the MCF523x to SDRAM. To use the tables, find the one that corresponds to the number of column address lines on the SDRAM and to the port size as seen by the MCF523x, which is not necessarily the SDRAM port size. For example, if two 1M x 16-bit SDRAMs together form a 2M x 32-bit memory, the port size is 32 bits. Most SDRAMs likely have fewer address lines than are shown in the tables, so follow only the connections shown until all SDRAM address lines are connected.

Table 22. MCF523x to SDRAM Interface (8-Bit Port, 9-Column Address Lines)

MCF523x Pins	A17	A16	A15	A14	A13	A12	A11	A10	A9	A18	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	17	16	15	14	13	12	11	10	9	18	19	20	21	22	23	24	25	26	27	28	29	30	31
Column	0	1	2	3	4	5	6	7	8														
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21	A22

Table 23. MCF523x to SDRAM Interface (8-Bit Port, 10-Column Address Lines)

MCF523x Pins	A17	A16	A15	A14	A13	A12	A11	A10	A9	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	17	16	15	14	13	12	11	10	9	19	20	21	22	23	24	25	26	27	28	29	30	31
Column	0	1	2	3	4	5	6	7	8	18												
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21

Table 24. MCF523x to SDRAM Interface (8-Bit Port, 11-Column Address Lines)

MCF523x Pins	A17	A16	A15	A14	A13	A12	A11	A10	A9	A19	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31	
Row	17	16	15	14	13	12	11	10	9	19	21	22	23	24	25	26	27	28	29	30	31	
Column	0	1	2	3	4	5	6	7	8	18	20											
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	

Interface Recommendations

Table 25. MCF523x to SDRAM Interface (8-Bit Port,12-Column Address Lines)

MCF523x Pins	A17	A16	A15	A14	A13	A12	A11	A10	A9	A19	A21	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	17	16	15	14	13	12	11	10	9	19	21	23	24	25	26	27	28	29	30	31
Column	0	1	2	3	4	5	6	7	8	18	20	22								
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19

Table 26. MCF523x to SDRAM Interface (8-Bit Port,13-Column Address Lines)

MCF523x Pins	A17	A16	A15	A14	A13	A12	A11	A10	A9	A19	A21	A23	A25	A26	A27	A28	A29	A30	A31
Row	17	16	15	14	13	12	11	10	9	19	21	23	25	26	27	28	29	30	31
Column	0	1	2	3	4	5	6	7	8	18	20	22	24						
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18

Table 27. MCF523x to SDRAM Interface (16-Bit Port, 8-Column Address Lines)

MCF523x Pins	A16	A15	A14	A13	A12	A11	A10	A9	A17	A18	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	16	15	14	13	12	11	10	9	17	18	19	20	21	22	23	24	25	26	27	28	29	30	31
Column	1	2	3	4	5	6	7	8															
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21	A22

Table 28. MCF523x to SDRAM Interface (16-Bit Port, 9-Column Address Lines)

MCF523x Pins	A16	A15	A14	A13	A12	A11	A10	A9	A18	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	16	15	14	13	12	11	10	9	18	19	20	21	22	23	24	25	26	27	28	29	30	31
Column	1	2	3	4	5	6	7	8	17													
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21

Table 29. MCF523x to SDRAM Interface (16-Bit Port, 10-Column Address Lines)

MCF523x Pins	A16	A15	A14	A13	A12	A11	A10	A9	A18	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31	
Row	16	15	14	13	12	11	10	9	18	20	21	22	23	24	25	26	27	28	29	30	31	
Column	1	2	3	4	5	6	7	8	17	19												
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	

Table 30. MCF523x to SDRAM Interface (16-Bit Port, 11-Column Address Lines)

MCF523x Pins	A16	A15	A14	A13	A12	A11	A10	A9	A18	A20	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	16	15	14	13	12	11	10	9	18	20	22	23	24	25	26	27	28	29	30	31
Column	1	2	3	4	5	6	7	8	17	19	21									
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19

Table 31. MCF523x to SDRAM Interface (16-Bit Port, 12-Column Address Lines)

MCF523x Pins	A16	A15	A14	A13	A12	A11	A10	A9	A18	A20	A22	A24	A25	A26	A27	A28	A29	A30	A31	
Row	16	15	14	13	12	11	10	9	18	20	22	24	25	26	27	28	29	30	31	
Column	1	2	3	4	5	6	7	8	17	19	21	23								
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	

Table 32. MCF523x to SDRAM Interface (16-Bit Port, 13-Column-Address Lines)

MCF523x Pins	A16	A15	A14	A13	A12	A11	A10	A9	A18	A20	A22	A24	A26	A27	A28	A29	A30	A31	
Row	16	15	14	13	12	11	10	9	18	20	22	24	26	27	28	29	30	31	
Column	1	2	3	4	5	6	7	8	17	19	21	23	25						
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	

Table 33. MCF523x to SDRAM Interface (32-Bit Port, 8-Column Address Lines)

MCF523x Pins	A15	A14	A13	A12	A11	A10	A9	A17	A18	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	15	14	13	12	11	10	9	17	18	19	20	21	22	23	24	25	26	27	28	29	30	31
Column	2	3	4	5	6	7	8	16														
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	A21

Table 34. MCF523x to SDRAM Interface (32-Bit Port, 9-Column Address Lines)

MCF523x Pins	A15	A14	A13	A12	A11	A10	A9	A17	A19	A20	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31	
Row	15	14	13	12	11	10	9	17	19	20	21	22	23	24	25	26	27	28	29	30	31	
Column	2	3	4	5	6	7	8	16	18													
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19	A20	

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Table 35. MCF523x to SDRAM Interface (32-Bit Port, 10-Column Address Lines)

MCF523x Pins	A15	A14	A13	A12	A11	A10	A9	A17	A19	A21	A22	A23	A24	A25	A26	A27	A28	A29	A30	A31
Row	15	14	13	12	11	10	9	17	19	21	22	23	24	25	26	27	28	29	30	31
Column	2	3	4	5	6	7	8	16	18	20										
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	A19

Table 36. MCF523x to SDRAM Interface (32-Bit Port, 11-Column Address Lines)

MCF523x Pins	A15	A14	A13	A12	A11	A10	A9	A17	A19	A21	A23	A24	A25	A26	A27	A28	A29	A30	A31	
Row	15	14	13	12	11	10	9	17	19	21	23	24	25	26	27	28	29	30	31	
Column	2	3	4	5	6	7	8	16	18	20	22									
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17	A18	

Table 37. MCF523x to SDRAM Interface (32-Bit Port, 12-Column Address Lines)

MCF523x Pins	A15	A14	A13	A12	A11	A10	A9	A17	A19	A21	A23	A25	A26	A27	A28	A29	A30	A31		
Row	15	14	13	12	11	10	9	17	19	21	23	25	26	27	28	29	30	31		
Column	2	3	4	5	6	7	8	16	18	20	22	24								
SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12	A13	A14	A15	A16	A17		

4.7.1.3 SDRAM Interfacing Example

The tables in the previous section can be used to configure the interface in the following example. To interface one 2M × 32-bit × 4 bank SDRAM component (8 columns) to the MCF523x, the connections would be as shown in Table 38.

Table 38. SDRAM Hardware Connections

SDRAM Pins	A0	A1	A2	A3	A4	A5	A6	A7	A8	A9	A10 = CMD	BA0	BA1
MCF523x Pins	A15	A14	A13	A12	A11	A10	A9	A17	A18	A19	A20	A21	A22

4.7.2 Ethernet PHY Transceiver Connection

The FEC supports both an MII interface for 10/100 Mbps Ethernet and a seven-wire serial interface for 10 Mbps Ethernet. The interface mode is selected by R_CNTRL[MII_MODE]. In MII mode, the 802.3 standard defines and the FEC module supports 18 signals. These are shown in Table 39.

Table 39. MII Mode

Signal Description	MCF523x Pin
Transmit clock	ETXCLK
Transmit enable	ETXEN
Transmit data	ETXD[3:0]
Transmit error	ETXER
Collision	ECOL
Carrier sense	ECRS
Receive clock	ERXCLK
Receive enable	ERXDV
Receive data	ERXD[3:0]
Receive error	ERXER
Management channel clock	EMDC
Management channel serial data	EMDIO

The serial mode interface operates in what is generally referred to as AMD mode. The MCF523x configuration for seven-wire serial mode connections to the external transceiver are shown in Table 40.

Table 40. Seven-Wire Mode Configuration

Signal Description	MCF523x Pin
Transmit clock	ETXCLK
Transmit enable	ETXEN
Transmit data	ETXD[0]
Collision	ECOL
Receive clock	ERXCLK
Receive enable	ERXDV
Receive data	ERXD[0]
Unused, configure as PB14	ERXER
Unused input, tie to ground	ECRS
Unused, configure as PB[13:11]	ERXD[3:1]
Unused output, ignore	ETXER
Unused, configure as PB[10:8]	ETXD[3:1]
Unused, configure as PB15	EMDC
Input after reset, connect to ground	EMDIO

Refer to the M523xEVB evaluation board user's manual for an example of how to connect an external PHY. Schematics for this board are accessible at the MCF523x site by navigating from: <http://e-www.motorola.com/> following the 32-bit Embedded Processors, 68K/ColdFire, MCF5xxx, MCF523x and M523xEVB links.

4.7.2.1 FlexCAN

The FlexCAN module interface to the CAN bus is composed of 2 pins: CANTX and CANRX, which are the serial transmitted data and the serial received data. The use of an external CAN transceiver to interface to the CAN bus is generally required. The transceiver is capable of driving the large current needed for the CAN bus and has current protection, against a defective CAN bus or defective stations.

4.7.3 BDM

Use the BDM interface as shown in the M523xEVB evaluation board user's manual. The schematics for this board are accessible at the MCF523x site by navigating from: <http://e-www.motorola.com/> following the 32-bit Embedded Processors, 68K/ColdFire, MCF5xxx, MCF523x and M523xEVB links.

5 Mechanicals and Part Numbers

This chapter contains drawings showing the pinout and the packaging and mechanical characteristics of the MCF523x devices.

5.1 Pinout—196 MAPBGA

Figure 2 shows a pinout of the MCF5232CVMxxx package.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	
A	VSS	TPUCH6	TPUCH3	TPUCH2	QSPI_DOUT	QSPI_CS0	U2RXD	U2TXD	$\overline{CS3}$	$\overline{CS6}$	$\overline{CS4}$	A20	A17	VSS	A
B	TPUCH8	TPUCH7	TPUCH4	TPUCH0	QSPI_DIN	$\overline{BS3}$	QSPI_CS1	$\overline{U1CTS}$	$\overline{CS7}$	$\overline{CS1}$	A23	A19	A16	A15	B
C	TPUCH10	TPUCH9	TPUCH5	TPUCH1	QSPI_CLK	$\overline{BS2}$	$\overline{BS0}$	$\overline{U1RTS}$	$\overline{CS2}$	$\overline{CS5}$	A22	A18	A14	A13	C
D	TPUCH13	TPUCH12	TPUCH11	NC	NC	Core VDD_4	$\overline{BS1}$	U1RXD/ CANRX0	U1TXD/ CAN0TX	$\overline{CS0}$	A21	A12	A11	A10	D
E	TPUCH14	TPUCH15	TCRCLK	DT0IN	VDD	VSS	VDD	SD_CKE	VSS	VDD	A9	A8	A7	A6	E
F	U0TXD	U0RXD	$\overline{U0CTS}$	DT0OUT	TEST	VSS	VDD	VSS	VDD	VDD	Core VDD_3	A5	A4	A3	F
G	DATA31	DATA30	$\overline{U0RTS}$	Core VDD_1	CLK MOD1	VDD	VSS	VDD	VSS	LTPU ODIS	A2	A1	A0	DTOUT3	G
H	DATA29	DATA28	DATA27	DATA26	CLK MOD0	VSS	VDD	VDD	VDD	UTPU ODIS	\overline{TA}	\overline{TP}	\overline{TS}	DTIN3	H
J	DATA25	DATA24	DATA23	DATA22	VSS	VDD	VSS	VDD	VSS	VDD	I2C_SCL	I2C_SDA	\overline{RW}	\overline{TEA}	J
K	DATA21	DATA20	DATA19	DATA18	VDD	VDD	VSS	VDD	JTAG_EN	\overline{RCON}	$\overline{SD_RAS}$	$\overline{SD_CAS}$	$\overline{SD_WE}$	CLKOUT	K
L	DATA17	DATA16	DATA10	Core VDD_2	DATA3	DT1IN	$\overline{IRQ5}$	$\overline{IRQ1}$	DT2OUT	PST0	DDATA0	$\overline{SD_CS1}$	$\overline{SD_CS0}$	VSSPLL	L
M	DATA15	DATA13	DATA9	DATA6	DATA2	DT1OUT	$\overline{IRQ6}$	$\overline{IRQ2}$	DT2IN	TDI/DSI	PST3	DDATA3	VDDPLL	EXTAL	M
N	DATA14	DATA12	DATA8	DATA5	DATA1	\overline{OE}	$\overline{IRQ7}$	$\overline{IRQ3}$	$\overline{TRST}/$ DSCLK	TDO/DSO	PST2	DDATA2	\overline{RESET}	XTAL	N
P	VSS	DATA11	DATA7	DATA4	DATA0	TSIZ1	TSIZ0	$\overline{IRQ4}$	TCLK/ PSTCLK	$\overline{TMS}/$ BKPT	PST1	DDATA1	\overline{RSTOUT}	VSS	P
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	

Figure 2. MCF5232CVMxxx Pinout (196 MAPBGA)

5.2 Package Dimensions—196 MAPBGA

Figure 3 shows MCF5232CVMxxx package dimensions.

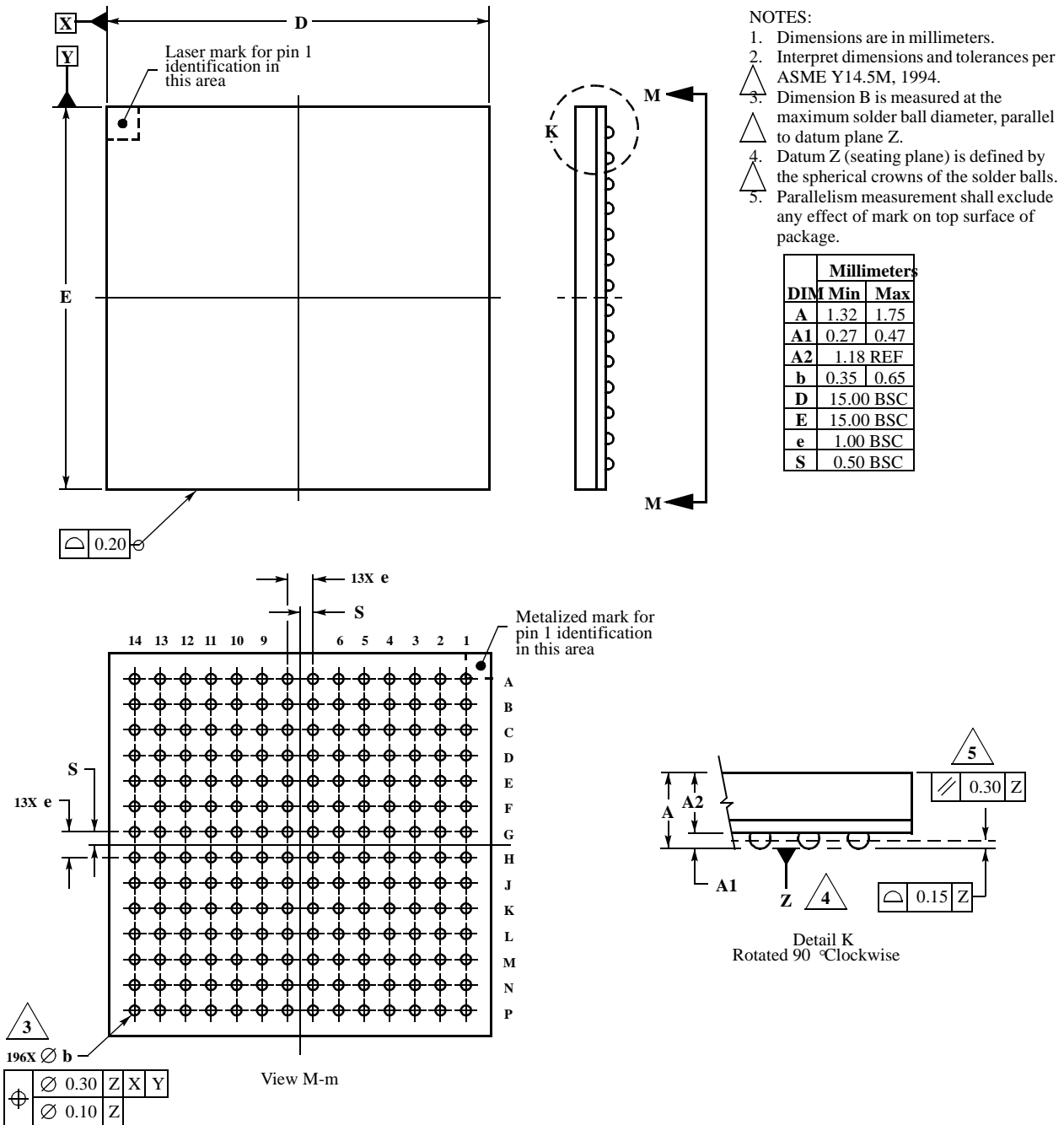


Figure 3. 196 MAPBGA Package Dimensions (Case No. 1128A-01)

5.2.1 Pinout—256 MAPBGA

Figure 4 through Figure 6 show pinouts of the MCF5233CVMxxx, MCF5234CVMxxx, and MCF5235CVMxxx packages.

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
A	VSS	TPUCH6	TPUCH4	TPUCH2	TPUCH17	TPUCH1	TPUCH0	Core VDD_4	BS1	BS0	U1RXD/ CANRX0	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	A
B	TPUCH8	TPUCH7	TPUCH5	TPUCH3	TPUCH18	TPUCH19	TPUCH16	QSPL_ CLK	BS2	QSPL_ CS1	U1RTS	CS3	CS1	A23	A20	A19	B
C	TPUCH10	TPUCH9	TPUCH25	TPUCH24	TPUCH22	TPUCH20	I2C_SDA/ U2RXD	QSPL_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	C
D	TPUCH12	TPUCH11	TPUCH27	TPUCH26	TPUCH23	TPUCH21	I2C_SCL/ U2TXD	QSPL_ DOUT	QSPL_ CS0	U2RXD/ CANRX1	U2TXD/ CAN1TX	CS2	CS0	A14	A15	A16	D
E	TPUCH14	TPUCH13	TPUCH29	TPUCH28	VSS	VDD	VDD	VDD	VDD	VDD	VDD	VSS	A10	A11	A12	A13	E
F	TCRCLK	TPUCH15	TPUCH31	TPUCH30	VDD	VSS	VDD	VDD	VDD	VDD	VSS	VDD	A7	A8	A9	VSS	F
G	U0CTS	U0RXD	DT0OUT	DT0IN	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	A4	A5	A6	Core VDD_3	G
H	Core VDD_1	U0TXD	U0RTS	NC	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	A0	A1	A2	A3	H
J	VSS	CLK MOD0	CLK MOD1	TEST	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	DATA28	DATA29	DATA30	DATA31	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	TEA	TA	TIP	TS	K
L	DATA24	DATA25	DATA26	DATA27	VDD	VSS	VDD	VDD	VDD	VDD	VSS	VDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SDA/ CANRX0	R/W	L
M	DATA21	DATA22	DATA23	NC	VSS	VDD	VDD	VDD	VDD	VDD	VDD	VSS	SD_CS0	SD_RAS	SD_CAS	CLKOUT	M
N	DATA19	DATA20	DATA13	DATA9	NC	DATA3	DATA0	TSIZ1	IRQ5	IRQ1	TRST/ DSCLK	PST0	JTAG_EN	DDATA3	SD_CS1	VSS	N
P	DATA17	DATA18	DATA12	DATA8	DATA5	DATA2	DT1IN	TSIZ0	IRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	P
R	DATA16	DATA15	DATA11	DATA7	DATA4	DATA1	DT1OUT	IRQ7	IRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_TEST	VSSPLL	XTAL	R
T	VSS	DATA14	DATA10	DATA6	Core VDD_2	VSS	OE	IRQ6	IRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RST_OUT	RESET	VSS	T
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 4. MCF5233CVMxxx Pinout (256 MAPBGA)

Package Dimensions—196 MAPBGA

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
A	VSS	TPUCH6	TPUCH4	TPUCH2	ETXD1	TPUCH1	TPUCH0	Core VDD_4	BS1	BS0	U1RXD/ CAN0RX	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	A
B	TPUCH8	TPUCH7	TPUCH5	TPUCH3	ETXD2	ETXD3	ETXD0	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	B
C	TPUCH10	TPUCH9	ERXD1	ERXD0	ETXCLK	ETXER	EMDIO	QSPI_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	C
D	TPUCH12	TPUCH11	ERXD3	ERXD2	ERXER	ETXEN	EMDC	QSPI_ DOUT	QSPI_C S0	U2RXD	U2TXD	CS2	CS0	A14	A15	A16	D
E	TPUCH14	TPUCH13	ERXCLK	ERXDV	VSS	VDD	VDD	VDD	VDD	VDD	VDD	VSS	A10	A11	A12	A13	E
F	TCRCLK	TPUCH15	ECOL	ECRS	VDD	VSS	VDD	VDD	VDD	VDD	VSS	VDD	A7	A8	A9	VSS	F
G	U0CTS	U0RXD	DT0OUT	DT0IN	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	A4	A5	A6	Core VDD_3	G
H	Core VDD_1	U0TXD	U0RTS	NC	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	A0	A1	A2	A3	H
J	VSS	CLK MOD0	CLK MOD1	TEST	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	DATA28	DATA29	DATA30	DATA31	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	TEA	TA	TIP	TS	K
L	DATA24	DATA25	DATA26	DATA27	VDD	VSS	VDD	VDD	VDD	VDD	VSS	VDD	SD_WE	I2C_SCL / CAN0TX	I2C_SD A/ CAN0RX	RW	L
M	DATA21	DATA22	DATA23	NC	VSS	VDD	VDD	VDD	VDD	VDD	VDD	VSS	SD_CS0	SD_RAS	SD_CAS	CLKOUT	M
N	DATA19	DATA20	DATA13	DATA9	NC	DATA3	DATA0	TSIZ1	IRQ5	IRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N
P	DATA17	DATA18	DATA12	DATA8	DATA5	DATA2	TIN1	TSIZ0	IRQ4	DT2IN	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	P
R	DATA16	DATA15	DATA11	DATA7	DATA4	DATA1	DT1OUT	IRQ7	IRQ3	DT2OUT	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
T	VSS	DATA14	DATA10	DATA6	Core VDD_2	VSS	OE	IRQ6	IRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RST OUT	RESET	VSS	T
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 5. MCF5234CVMxxx Pinout (256 MAPBGA)

Package Dimensions—196 MAPBGA

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	
A	VSS	TPUCH6	TPUCH4	TPUCH2	TPUCH17/ ETXD1	TPUCH1	TPUCH0	Core VDD_4	BS1	BS0	U1RXD/ CANRX0	U1TXD/ CAN0TX	CS6	CS4	A21	VSS	A
B	TPUCH8	TPUCH7	TPUCH5	TPUCH3	TPUCH18/ ETXD2	TPUCH19/ ETXD3	TPUCH16/ ETXD0	QSPI_ CLK	BS2	QSPI_ CS1	U1RTS	CS3	CS1	A23	A20	A19	B
C	TPUCH1 0	TPUCH9	TPUCH25/ ERXD1	TPUCH24/ ERXD0	TPUCH22/ ETXCLK	TPUCH20/ ETXER	I2C_SDA/ U2RXD/ EMDIO	QSPI_ DIN	BS3	SD_CKE	U1CTS	CS7	CS5	A22	A18	A17	C
D	TPUCH1 2	TPUCH1 1	TPUCH27/ ERXD3	TPUCH26/ ERXD2	TPUCH23/ ERXER	TPUCH21/ ETXEN	I2C_SCL/ U2TXD/ EMDC	QSPI_ DOUT	QSPI_ CS0	U2RXD/ CANRX1	U2TXD/ CAN1TX	CS2	CS0	A14	A15	A16	D
E	TPUCH1 4	TPUCH1 3	TPUCH29/ ERXCLK	TPUCH28/ ERXDV	VSS	VDD	VDD	VDD	VDD	VDD	VDD	VSS	A10	A11	A12	A13	E
F	TCRCLK	TPUCH1 5	TPUCH31/ ECOL	TPUCH30/ ECSR	VDD	VSS	VDD	VDD	VDD	VDD	VSS	VDD	A7	A8	A9	VSS	F
G	U0CTS0	U0RXD	DT0OUT	DT0IN	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	A4	A5	A6	Core VDD_3	G
H	Core VDD_1	U0TXD	U0RTS	NC	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	A0	A1	A2	A3	H
J	VSS	CLK MOD0	CLK MOD1	TEST	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	UTPU ODIS	LTPU ODIS	DT3IN	DT3OUT	J
K	DATA28	DATA29	DATA30	DATA31	VDD	VDD	VSS	VSS	VSS	VSS	VDD	VDD	TEA	TA	TIP	TS	K
L	DATA24	DATA25	DATA26	DATA27	VDD	VSS	VDD	VDD	VDD	VDD	VSS	VDD	SD_WE	I2C_SCL/ CAN0TX	I2C_SD A/ CANRX0	R/W	L
M	DATA21	DATA22	DATA23	eTPU/ EthENB	VSS	VDD	VDD	VDD	VDD	VDD	VDD	VSS	SD_CS0	SD_RAS	SD_CAS	CLKOUT	M
N	DATA19	DATA20	DATA13	DATA9	NC	DATA3	DATA0	TSIZ1	IRQ5	IRQ1	TRST/ DSCLK	PST0	JTAG_ EN	DDATA3	SD_CS1	VSS	N
P	DATA17	DATA18	DATA12	DATA8	DATA5	DATA2	TIN1	TSIZ0	IRQ4	TIN2	TMS/ BKPT	PST1	RCON	DDATA2	VDDPLL	EXTAL	P
R	DATA16	DATA15	DATA11	DATA7	DATA4	DATA1	TOUT1	IRQ7	IRQ3	TOUT2	TDO/ DSO	PST2	DDATA0	PLL_ TEST	VSSPLL	XTAL	R
T	VSS	DATA14	DATA10	DATA6	Core VDD_2	VSS	OE	IRQ6	IRQ2	TCLK/ PSTCLK	TDI/DSI	PST3	DDATA1	RSTOUT	RESET	VSS	T
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	

Figure 6. MCF5235CVMxxx Pinout (256 MAPBGA)

5.2.2 Package Dimensions—256 MAPBGA

Figure 7 shows MCF5235CVMxxx, MCF5234CVMxxx, and MCF5233CVMxx package dimensions.

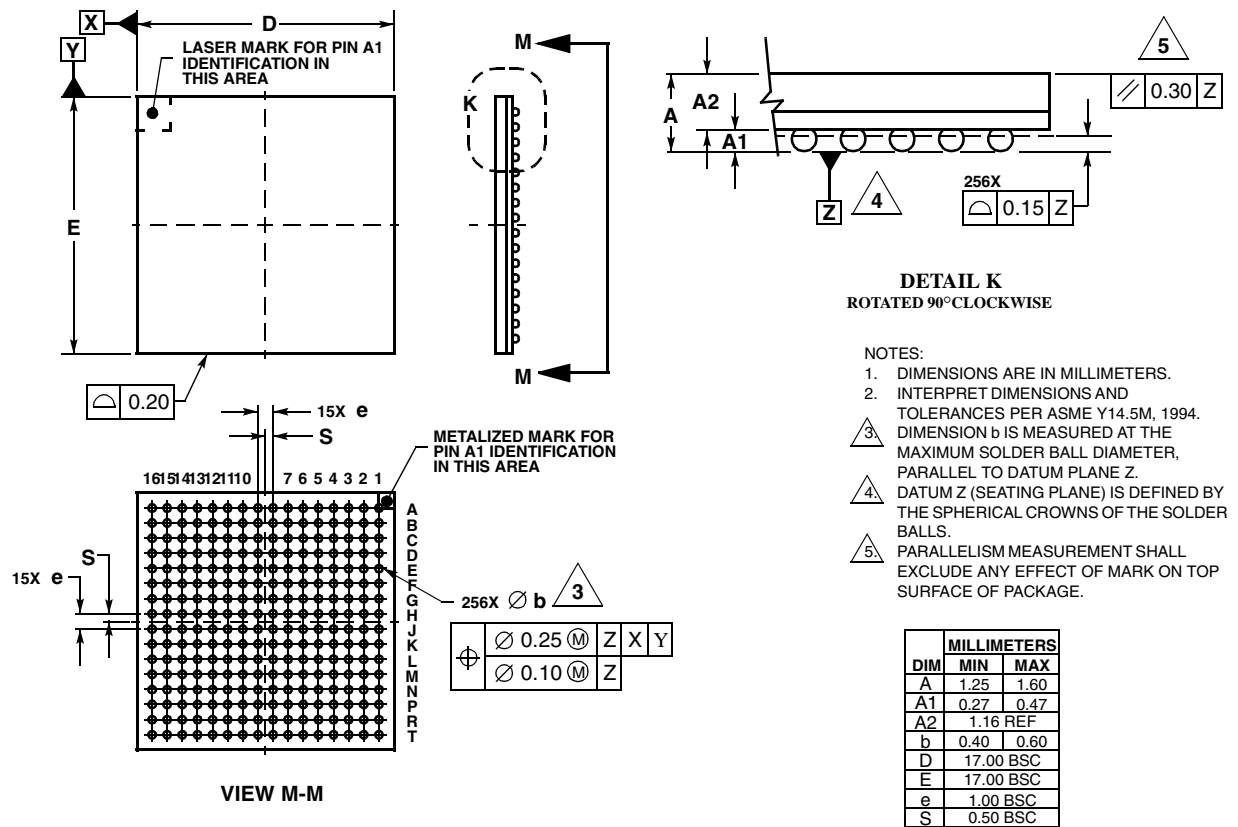


Figure 7. 256 MAPBGA Package Outline

5.3 Pinout—160 QFP

Figure 8 shows a pinout of the MCF5232CABxxx package.

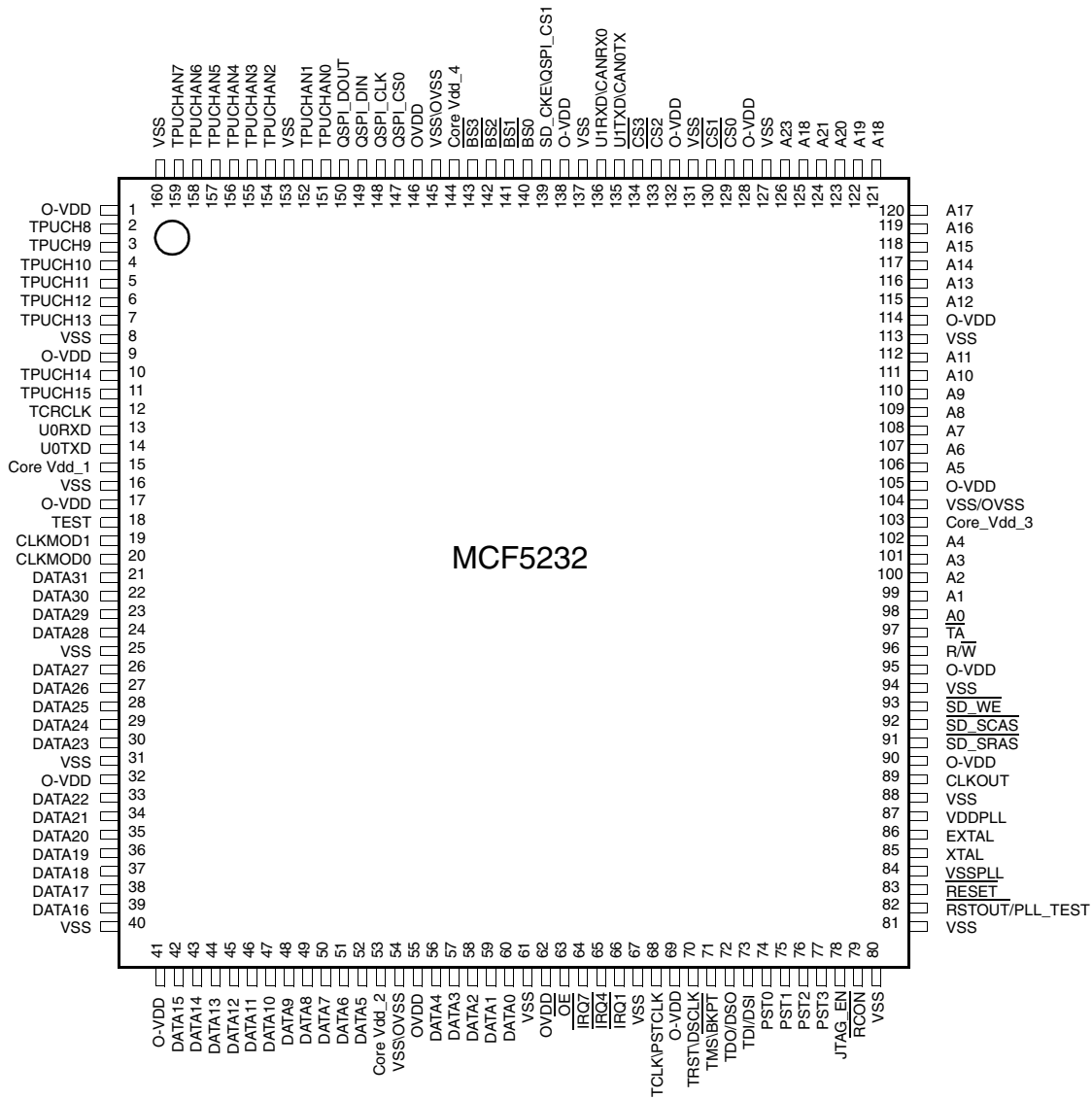
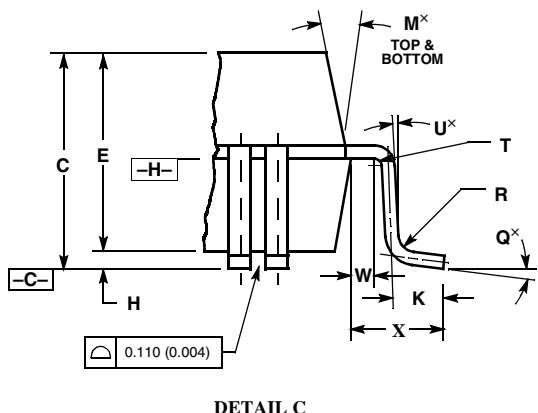
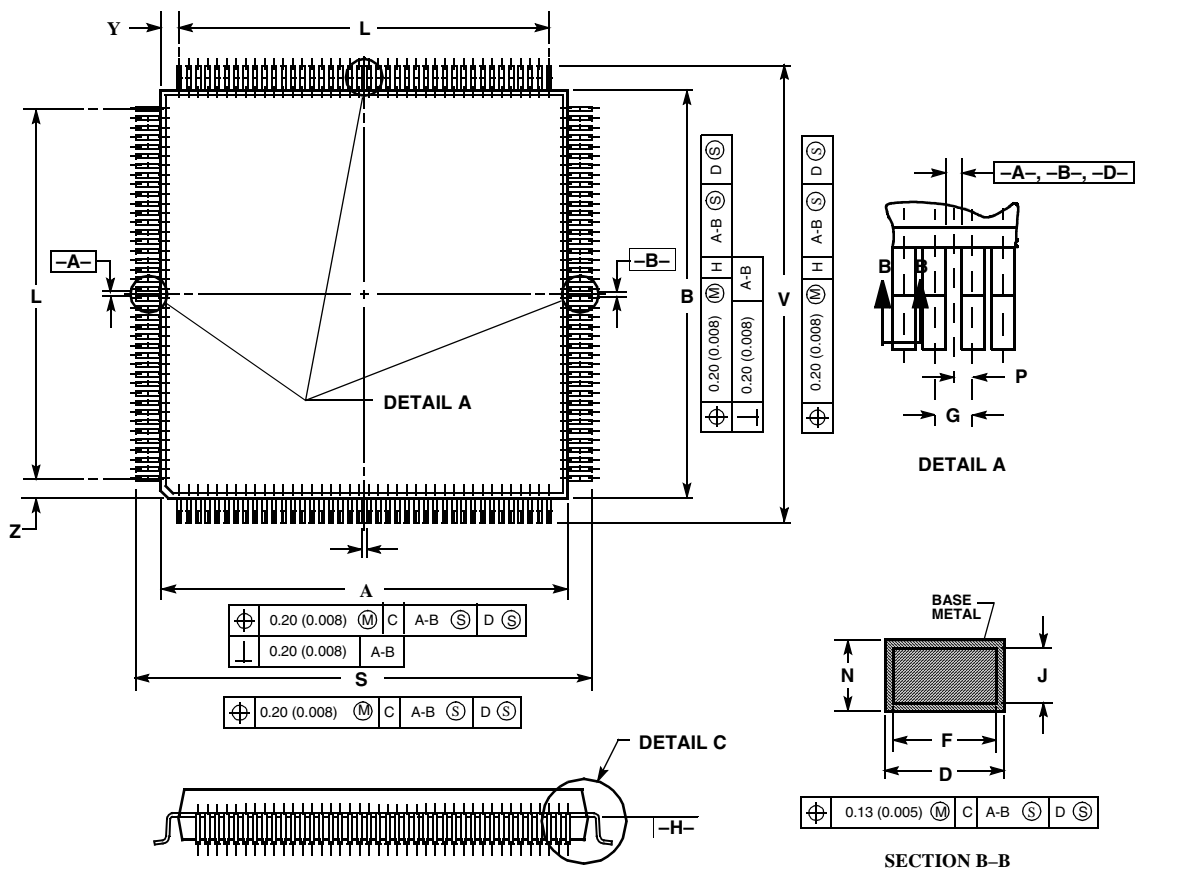


Figure 8. MCF5232CABxxx Pinout (160 QFP)

5.4 Package Dimensions—160 QFP

Figure 9 shows MCF5232CAB80 package dimensions.



- NOTES
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETER
 3. DATUM PLAN -H- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
 4. DATUMS -A-, -B-, AND -D- TO BE DETERMINED AT DATUM PLANE -H-.
 5. DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE -C-.
 6. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
 7. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	27.90	28.10	1.098	1.106
B	27.90	28.10	1.098	1.106
C	3.35	3.85	0.132	1.106
D	0.22	0.38	0.009	0.015
E	3.20	3.50	0.126	0.138
F	0.22	0.33	0.009	0.013
G	0.65 BSC		0.026 REF	
H	0.25	0.35	0.010	0.014
J	0.11	0.23	0.004	0.009
K	0.70	0.90	0.028	0.035
L	25.35 BSC		0.998 REF	
M	5	16	5	16
N	0.11	0.19	0.004	0.007
P	0.325 BSC		0.013 REF	
Q	0	7	0	7
R	0.13	0.30	0.005	0.012
S	31.00	31.40	1.220	1.236
T	0.13		0.005	
U	0		0	
V	31.00	31.40	1.220	1.236
W	0.4		0.016	
X	1.60 REF		0.063 REF	
Y	1.33 REF		0.052 REF	
Z	1.33 REF		0.052 REF	

Case 864A-03

Figure 9. 160 QFP Package Dimensions

5.5 Ordering Information

Table 41. Orderable Part Numbers

Motorola Part Number	Description	Speed	Temperature
MCF5232CAB80	MCF5232 RISC Microprocessor, 160 QFP	80MHz	-40° to +85° C
MCF5232CVM100	MCF5232 RISC Microprocessor, 196 MAPBGA	100MHz	-40° to +85° C
MCF5232CVM150	MCF5232 RISC Microprocessor, 196 MAPBGA	150MHz	-40° to +85° C
MCF5233CVM100	MCF5232 RISC Microprocessor, 256 MAPBGA	100MHz	-40° to +85° C
MCF5233CVM150	MCF5232 RISC Microprocessor, 256 MAPBGA	150MHz	-40° to +85° C
MCF5234CVM100	MCF5232 RISC Microprocessor, 256 MAPBGA	100MHz	-40° to +85° C
MCF5234CVM150	MCF5232 RISC Microprocessor, 256 MAPBGA	150MHz	-40° to +85° C
MCF5235CVM100	MCF5232 RISC Microprocessor, 256 MAPBGA	100MHz	-40° to +85° C
MCF5235CVM150	MCF5232 RISC Microprocessor, 256 MAPBGA	150MHz	-40° to +85° C

6 Preliminary Electrical Characteristics

This chapter contains electrical specification tables and reference timing diagrams for the MCF5232 microcontroller unit. This section contains detailed information on power considerations, DC/AC electrical characteristics, and AC timing specifications of MCF5232.

The electrical specifications are preliminary and are from previous designs or design simulations. These specifications may not be fully tested or guaranteed at this early stage of the product life cycle, however for production silicon these specifications will be met. Finalized specifications will be published after complete characterization and device qualifications have been completed.

NOTE

The parameters specified in this processor document supersede any values found in the module specifications.

6.1 Maximum Ratings

Table 42. Absolute Maximum Ratings ^{1, 2}

Rating	Symbol	Value	Unit
Core Supply Voltage	V_{DD}	- 0.5 to +2.0	V
Pad Supply Voltage	OV_{DD}	- 0.3 to +4.0	V
Clock Synthesizer Supply Voltage	V_{DDPLL}	- 0.3 to +4.0	V
Digital Input Voltage ³	V_{IN}	- 0.3 to + 4.0	V

Thermal Characteristics

Table 42. Absolute Maximum Ratings ^{1, 2}

Rating	Symbol	Value	Unit
Instantaneous Maximum Current Single pin limit (applies to all pins) ^{3, 4, 5}	I_D	25	mA
Operating Temperature Range (Packaged)	T_A ($T_L - T_H$)	- 40 to 85	°C
Storage Temperature Range	T_{stg}	- 65 to 150	°C

¹ Functional operating conditions are given in DC Electrical Specifications. Absolute Maximum Ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Continued operation at these levels may affect device reliability or cause permanent damage to the device.

² This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., either V_{SS} or OV_{DD}).

³ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

⁴ All functional non-supply pins are internally clamped to V_{SS} and OV_{DD} .

⁵ Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > OV_{DD}$) is greater than I_{DD} , the injection current may flow out of OV_{DD} and could result in external power supply going out of regulation. Insure external OV_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power (ex; no clock). Power supply must maintain regulation within operating OV_{DD} range during instantaneous and operating maximum current conditions.

6.2 Thermal Characteristics

Table lists thermal resistance values

Table 43. Thermal Characteristics

Characteristic		Symbol	256 MAPBGA	196 MAPBGA	160QFP	Unit
Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JMA}	26 ^{1, 2}	32 ^{3, 4}	40 ^{5, 6}	°C/W
Junction to ambient (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	23 ^{5,6}	29 ^{5,6}	36 ^{5,6}	°C/W
Junction to board		θ_{JB}	15 ⁷	20 ⁸	25 ⁹	°C/W
Junction to case		θ_{JC}	10 ¹⁰	10 ¹¹	10 ¹²	°C/W
Junction to top of package		Ψ_{jt}	2 ^{5, 13}	2 ^{5, 14}	2 ^{5, 15}	°C/W
Maximum operating junction temperature		T_j	TBD	TBD	TBD	°C

¹ θ_{JMA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Motorola recommends the use of θ_{JMA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.

² Per JEDEC JESD51-6 with the board horizontal.

- ³ θ_{JMA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Motorola recommends the use of θ_{JMA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.
- ⁴ Per JEDEC JESD51-6 with the board horizontal.
- ⁵ θ_{JMA} and Ψ_{jt} parameters are simulated in conformance with EIA/JESD Standard 51-2 for natural convection. Motorola recommends the use of θ_{JMA} and power dissipation specifications in the system design to prevent device junction temperatures from exceeding the rated specification. System designers should be aware that device junction temperatures can be significantly influenced by board layout and surrounding devices. Conformance to the device junction temperature specification can be verified by physical measurement in the customer's system using the Ψ_{jt} parameter, the device power dissipation, and the method described in EIA/JESD Standard 51-2.
- ⁶ Per JEDEC JESD51-6 with the board horizontal.
- ⁷ Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- ⁸ Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- ⁹ Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- ¹⁰ Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
- ¹¹ Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
- ¹² Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
- ¹³ Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.
- ¹⁴ Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.
- ¹⁵ Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.

The average chip-junction temperature (T_J) in °C can be obtained from:

$$T_J = T_A + (P_D \times \theta_{JMA}) \quad (1)$$

Where:

T_A = Ambient Temperature, °C

θ_{JMA} = Package Thermal Resistance, Junction-to-Ambient, °C/W

$P_D = P_{INT} + P_{I/O}$

$P_{INT} = I_{DD} \times V_{DD}$, Watts - Chip Internal Power

$P_{I/O}$ = Power Dissipation on Input and Output Pins — User Determined

For most applications $P_{I/O} < P_{INT}$ and can be ignored. An approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected) is:

$$P_D = K + (T_J + 273^\circ\text{C}) \quad (2)$$

Solving equations 1 and 2 for K gives:

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$$K = P_D \times (T_A + 273 \text{ }^\circ\text{C}) + \Theta_{JMA} \times P_D^2 \quad (3)$$

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and T_J can be obtained by solving equations (1) and (2) iteratively for any value of T_A .

6.3 DC Electrical Specifications

Table 44. DC Electrical Specifications ¹

Characteristic	Symbol	Min	Max	Unit
Core Supply Voltage	V_{DD}	1.35	1.65	V
Pad Supply Voltage	OV_{DD}	3	3.6	V
Input High Voltage	V_{IH}	$0.7 \times OV_{DD}$	3.65	V
Input Low Voltage	V_{IL}	$V_{SS} - 0.3$	$0.35 \times OV_{DD}$	V
Input Hysteresis	V_{HYS}	$0.06 \times OV_{DD}$	—	mV
Input Leakage Current $V_{in} = V_{DD}$ or V_{SS} , Input-only pins	I_{in}	-1.0	1.0	μA
High Impedance (Off-State) Leakage Current $V_{in} = V_{DD}$ or V_{SS} , All input/output and output pins	I_{OZ}	-1.0	1.0	μA
Output High Voltage (All input/output and all output pins) $I_{OH} = -5.0 \text{ mA}$	V_{OH}	$OV_{DD} - 0.5$	—	V
Output Low Voltage (All input/output and all output pins) $I_{OL} = 5.0 \text{ mA}$	V_{OL}	—	0.5	V
Weak Internal Pull Up Device Current, tested at V_{IL} Max. ²	I_{APU}	-10	-130	μA
Input Capacitance ³ All input-only pins All input/output (three-state) pins	C_{in}	— —	7 7	pF
Load Capacitance ⁴ Low drive strength High drive strength	C_L		25 50	pF
Core Operating Supply Current ⁵ Master Mode	I_{DD}	—	TBD	mA
Pad Operating Supply Current Master Mode Low Power Modes	OI_{DD}	— —	TBD TBD	mA μA
DC Injection Current ^{3, 6, 7, 8} $V_{NEGCLAMP} = V_{SS} - 0.3 \text{ V}$, $V_{POSCLAMP} = V_{DD} + 0.3$ Single Pin Limit Total processor Limit, Includes sum of all stressed pins	I_{IC}	-1.0 -10	1.0 10	mA

¹ Refer to Table 45 for additional PLL specifications.

² Refer to the MCF5232 signals section for pins having weak internal pull-up devices.

³ This parameter is characterized before qualification rather than 100% tested.

⁴ pF load ratings are based on DC loading and are provided as an indication of driver strength. High speed interfaces require transmission line analysis to determine proper drive strength and termination. See [High Speed Signal Propagation: Advanced Black Magic](#) by Howard W. Johnson for design guidelines.

- ⁵ Current measured at maximum system clock frequency, all modules active, and default drive strength with matching load.
- ⁶ All functional non-supply pins are internally clamped to V_{SS} and their respective V_{DD} .
- ⁷ Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.
- ⁸ Power supply must maintain regulation within operating V_{DD} range during instantaneous and operating maximum current conditions. If positive injection current ($V_{in} > V_{DD}$) is greater than I_{DD} , the injection current may flow out of V_{DD} and could result in external power supply going out of regulation. Insure external V_{DD} load will shunt current greater than maximum injection current. This will be the greatest risk when the processor is not consuming power. Examples are: if no system clock is present, or if clock rate is very low which would reduce overall power consumption. Also, at power-up, system clock is not present during the power-up sequence until the PLL has attained lock.

6.4 Oscillator and PLLMRFM Electrical Characteristics

Table 45. HiP7 PLLMRFM Electrical Specifications ¹

Num	Characteristic	Symbol	Min. Value	Max. Value	Unit
1	PLL Reference Frequency Range				MHz
	Crystal reference	$f_{ref_crystal}$	8	25	
	External reference 1:1 mode (NOTE: $f_{sys/2} = 2 \times f_{ref_1:1}$)	f_{ref_ext} $f_{ref_1:1}$	8 24	25 75	
2	Core frequency	f_{sys}		150	MHz
	CLKOUT Frequency ²		0	75	MHz
	External reference On-Chip PLL Frequency	$f_{sys/2}$	$f_{ref} \div 32$	75	MHz
3	Loss of Reference Frequency ^{3, 5}	f_{LOR}	100	1000	kHz
4	Self Clocked Mode Frequency ^{4, 5}	f_{SCM}	TBD	TBD	MHz
5	Crystal Start-up Time ^{5, 6}	t_{cst}	—	10	ms
6	EXTAL Input High Voltage				
	Crystal Mode ⁷ All other modes (Dual Controller (1:1), Bypass, External)	V_{IHEXT} V_{IHEXT}	TBD TBD	TBD TBD	V V
7	EXTAL Input Low Voltage				
	Crystal Mode ⁷ All other modes (Dual Controller (1:1), Bypass, External)	V_{ILEXT} V_{ILEXT}	TBD TBD	TBD TBD	V V
8	XTAL Output High Voltage $I_{OH} = 1.0$ mA	V_{OH}	TBD	—	V
9	XTAL Output Low Voltage $I_{OL} = 1.0$ mA	V_{OL}	—	TBD	V
10	XTAL Load Capacitance ⁵		5	30	pF
11	PLL Lock Time ^{5, 8,14}	t_{pll}	—	750	μ s
12	Power-up To Lock Time ^{5, 6, 9}				
	With Crystal Reference (includes 5 time) Without Crystal Reference ¹⁰	t_{plk}	— —	11 750	ms μ s

Table 45. HiP7 PLLRFM Electrical Specifications ¹

Num	Characteristic	Symbol	Min. Value	Max. Value	Unit
13	1:1 Mode Clock Skew (between CLKOUT and EXTAL) ¹¹	t_{skew}	-1	1	ns
14	Duty Cycle of reference ⁵	t_{dc}	40	60	%
15	Frequency un-LOCK Range	f_{UL}	-3.8	4.1	% $f_{sys/2}$
16	Frequency LOCK Range	f_{LCK}	-1.7	2.0	% $f_{sys/2}$
17	CLKOUT Period Jitter, ^{5, 6, 9, 12, 13} Measured at $f_{sys/2}$ Max Peak-to-peak Jitter (Clock edge to clock edge) Long Term Jitter (Averaged over 2 ms interval)	C_{jitter}	— —	5.0 .01	% $f_{sys/2}$
18	Frequency Modulation Range Limit ^{14, 15} ($f_{sys/2}$ Max must not be exceeded)	C_{mod}	0.8	2.2	% $f_{sys/2}$
19	ICO Frequency. $f_{ico} = f_{ref} * 2 * (MFD+2)$ ¹⁶	f_{ico}	48	75	MHz

¹ All values given are initial design targets and subject to change.

² All internal registers retain data at 0 Hz.

³ "Loss of Reference Frequency" is the reference frequency detected internally, which transitions the PLL into self clocked mode.

⁴ Self clocked mode frequency is the frequency that the PLL operates at when the reference frequency falls below f_{LOR} with default MFD/RFD settings.

⁵ This parameter is guaranteed by characterization before qualification rather than 100% tested.

⁶ Proper PC board layout procedures must be followed to achieve specifications.

⁷ This parameter is guaranteed by design rather than 100% tested.

⁸ This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).

⁹ Assuming a reference is available at power up, lock time is measured from the time V_{DD} and V_{DDSYN} are valid to \overline{RSTOUT} negating. If the crystal oscillator is being used as the reference for the PLL, then the crystal start up time must be added to the PLL lock time to determine the total start-up time.

¹⁰ $t_{ipll} = (64 * 4 * 5 + 5 * \tau) * T_{ref}$, where $T_{ref} = 1/F_{ref_crystal} = 1/F_{ref_ext} = 1/F_{ref_1:1}$, and $\tau = 1.57 * 10^{-6} * 2 * (MFD + 2)$.

¹¹ PLL is operating in 1:1 PLL mode.

¹² Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum $f_{sys/2}$. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDSYN} and V_{SSSYN} and variation in crystal oscillator frequency increase the C_{jitter} percentage for a given interval.

¹³ Values are with frequency modulation disabled. If frequency modulation is enabled, jitter is the sum of $C_{jitter} + C_{mod}$.

¹⁴ Modulation percentage applies over an interval of 10 μ s, or equivalently the modulation rate is 100KHz.

¹⁵ Modulation rate selected must not result in $f_{sys/2}$ value greater than the $f_{sys/2}$ maximum specified value. Modulation range determined by hardware design.

¹⁶ $f_{sys/2} = f_{ico} / (2 * 2^{RFD})$

6.5 External Interface Timing Characteristics

Table 46 lists processor bus input timings.

NOTE

All processor bus timings are synchronous; that is, input setup/hold and output delay with respect to the rising edge of a reference clock. The reference clock is the CLKOUT output.

All other timing relationships can be derived from these values.

Table 46. Processor Bus Input Timing Specifications

Name	Characteristic ¹	Symbol	Min	Max	Unit
freq	System bus frequency	$f_{\text{sys}/2}$	40	75	MHz
B0	CLKOUT period	t_{cyc}		1/75	ns
Control Inputs					
B1a	Control input valid to CLKOUT high ²	t_{CVCH}	9	—	ns
B1b	$\overline{\text{BKPT}}$ valid to CLKOUT high ³	t_{BKVCH}	9	—	ns
B2a	CLKOUT high to control inputs invalid ²	t_{CHCII}	0	—	ns
B2b	CLKOUT high to asynchronous control input $\overline{\text{BKPT}}$ invalid ³	t_{BKNCH}	0	—	ns
Data Inputs					
B4	Data input (D[31:0]) valid to CLKOUT high	t_{DIVCH}	4	—	ns
B5	CLKOUT high to data input (D[31:0]) invalid	t_{CHDII}	0	—	ns

¹ Timing specifications are tested using full drive strength pad configurations in a 50ohm transmission line environment..

² $\overline{\text{TEA}}$ and $\overline{\text{TA}}$ pins are being referred to as control inputs.

³ Refer to figure A-19.

Timings listed in Table 46 are shown in Figure 10 & Figure A-3.

Processor Bus Output Timing Specifications

* The timings are also valid for inputs sampled on the negative clock edge.

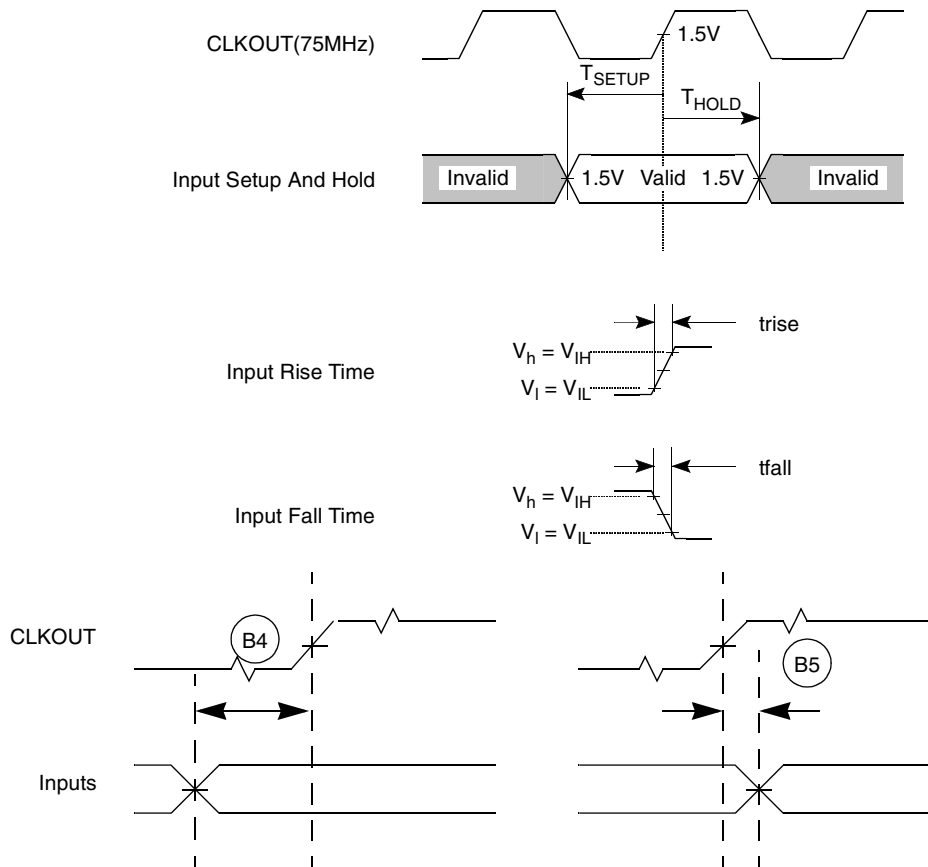


Figure 10. General Input Timing Requirements

6.6 Processor Bus Output Timing Specifications

Table 47 lists processor bus output timings.

Table 47. External Bus Output Timing Specifications

Name	Characteristic	Symbol	Min	Max	Unit
Control Outputs					
B6a	CLKOUT high to chip selects valid ¹	t_{CHCV}	—	$0.5t_{\text{CYC}} + 5$	ns
B6b	CLKOUT high to byte enables ($\overline{\text{BS}}[3:0]$) valid ²	t_{CHBV}	—	$0.5t_{\text{CYC}} + 5$	ns
B6c	CLKOUT high to output enable ($\overline{\text{OE}}$) valid ³	t_{CHOV}	—	$0.5t_{\text{CYC}} + 5$	ns
B7	CLKOUT high to control output ($\overline{\text{BS}}[3:0]$, $\overline{\text{OE}}$) invalid	t_{CHCOI}	$0.5t_{\text{CYC}} + 1.5$	—	ns
B7a	CLKOUT high to chip selects invalid	t_{CHCI}	$0.5t_{\text{CYC}} + 1.5$	—	ns

Table 47. External Bus Output Timing Specifications (continued)

Name	Characteristic	Symbol	Min	Max	Unit
Address and Attribute Outputs					
B8	CLKOUT high to address (A[23:0]) and control (\overline{TS} , $\overline{TSIZ}[1:0]$, \overline{TIP} , R/W) valid	t_{CHAV}	—	9	ns
B9	CLKOUT high to address (A[23:0]) and control (\overline{TS} , $\overline{TSIZ}[1:0]$, \overline{TIP} , R/W) invalid	t_{CHAI}	1.5	—	ns
Data Outputs					
B11	CLKOUT high to data output (D[31:0]) valid	t_{CHDOV}	—	9	ns
B12	CLKOUT high to data output (D[31:0]) invalid	t_{CHDOI}	1.5	—	ns
B13	CLKOUT high to data output (D[31:0]) high impedance	t_{CHDOZ}	—	9	ns

¹ \overline{CS} transitions after the falling edge of CLKOUT.

² \overline{BS} transitions after the falling edge of CLKOUT.

³ \overline{OE} transitions after the falling edge of CLKOUT.

Read/write bus timings listed in Table 47 are shown in Figure 11, Figure 12, and Figure 13.

Processor Bus Output Timing Specifications

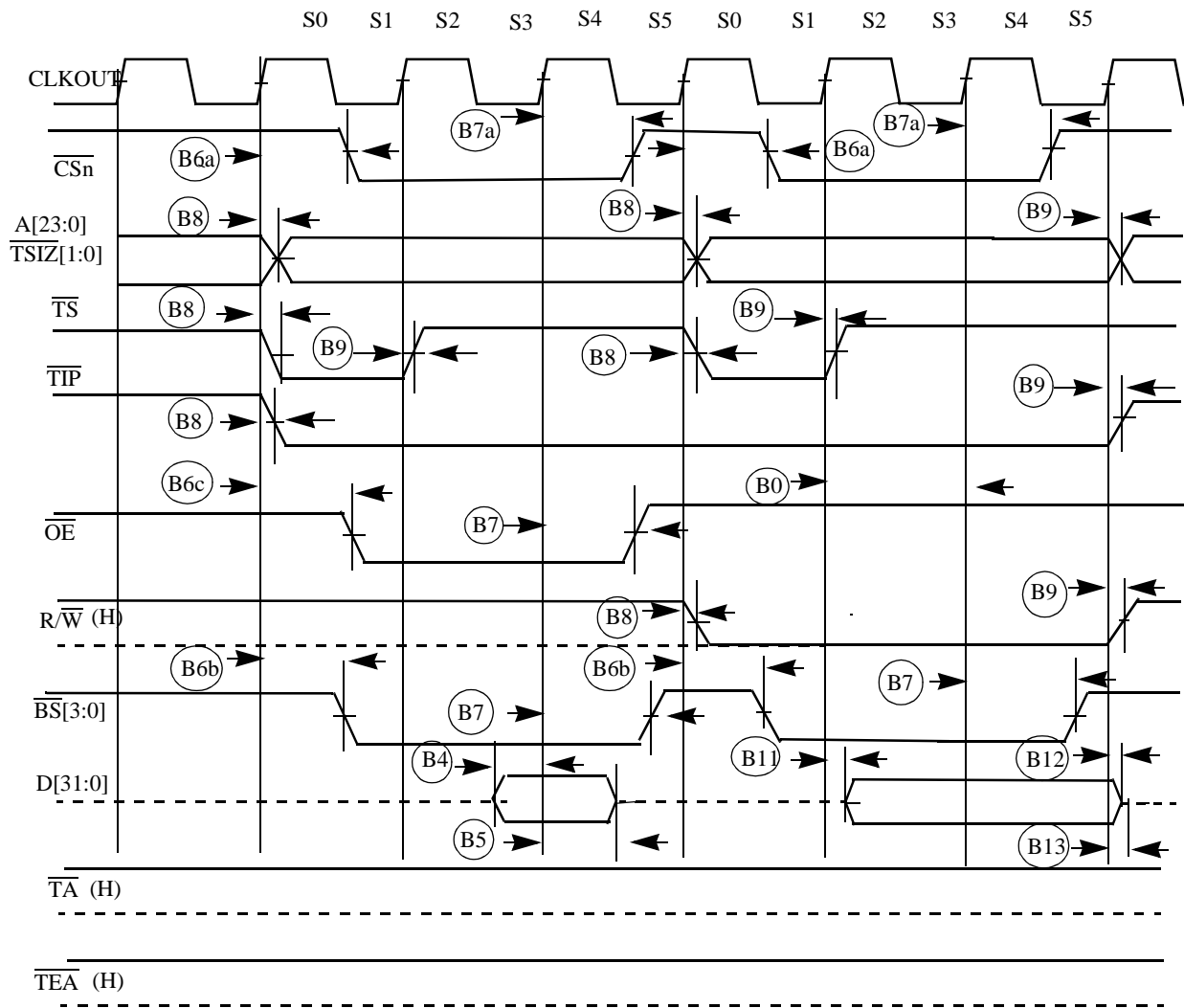


Figure 11. Read/Write (Internally Terminated) SRAM Bus Timing

Figure 12 shows a bus cycle terminated by $\overline{\text{TA}}$ showing timings listed in Table 47.

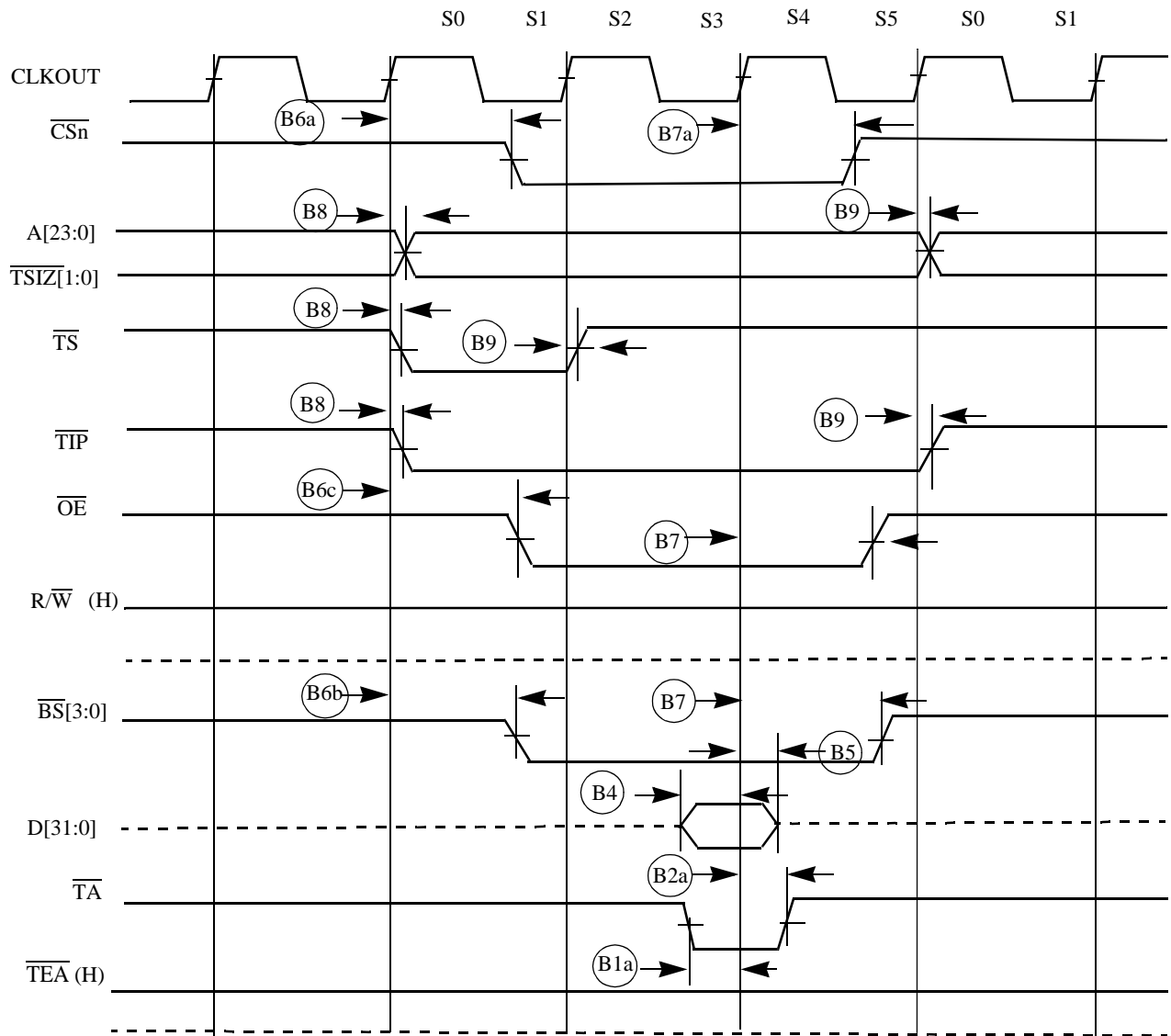


Figure 12. SRAM Read Bus Cycle Terminated by $\overline{\text{TA}}$

Processor Bus Output Timing Specifications

Figure 13 shows an SRAM bus cycle terminated by $\overline{\text{TEA}}$ showing timings listed in Table 47.

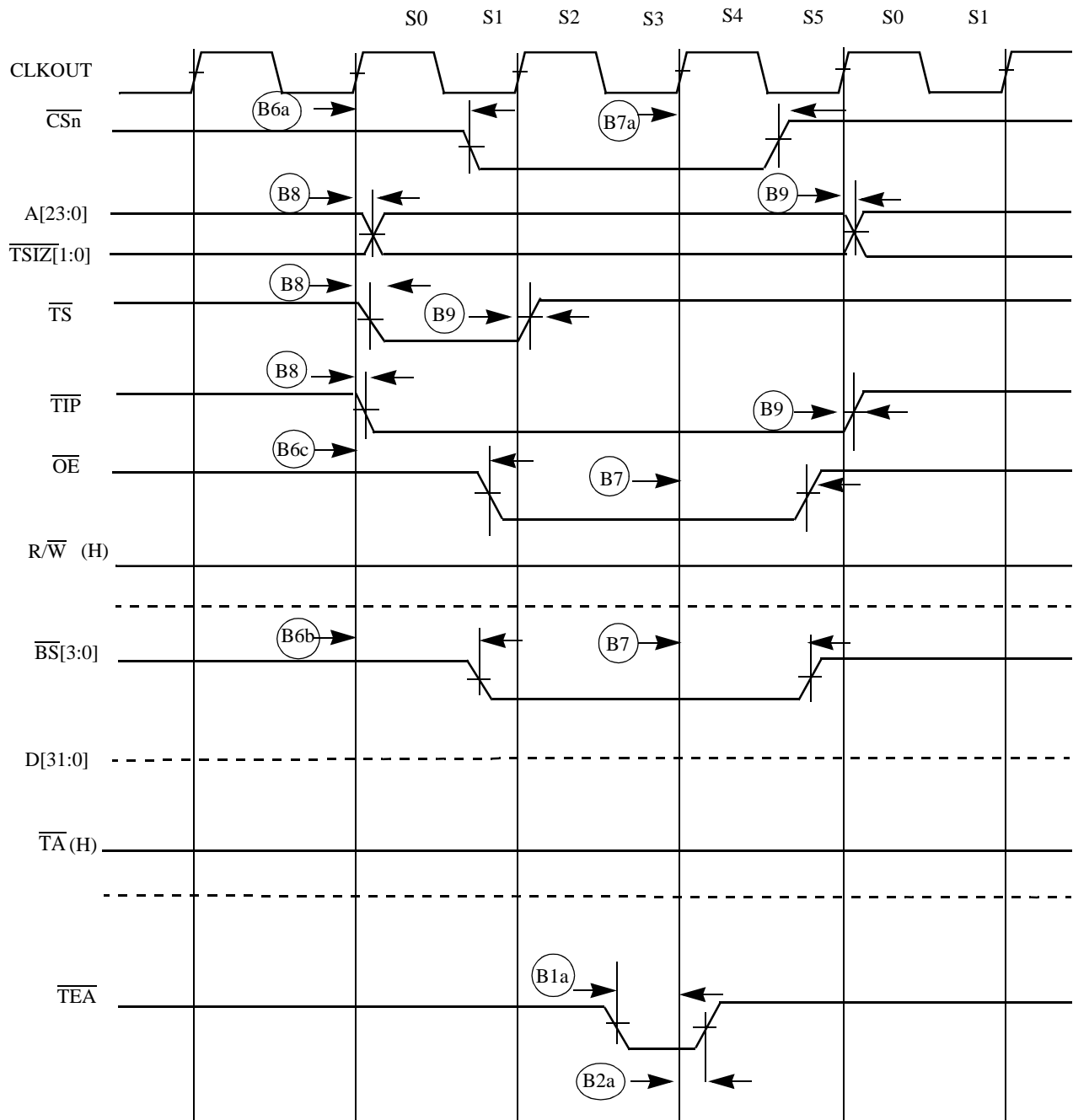


Figure 13. SRAM Read Bus Cycle Terminated by $\overline{\text{TEA}}$

Figure 14 shows an SDRAM read cycle.

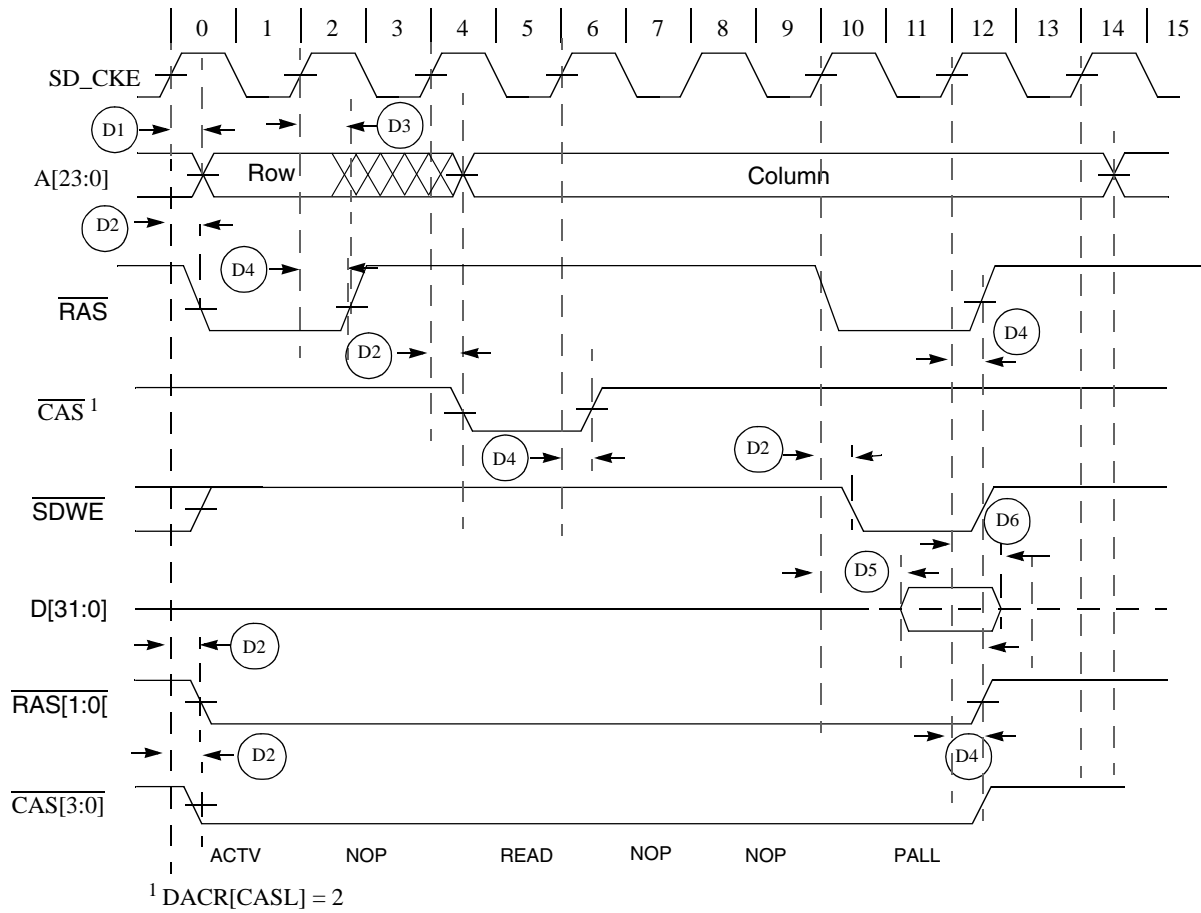


Figure 14. SDRAM Read Cycle

Table 48. SDRAM Timing

NUM	Characteristic	Symbol	Min	Max	Unit
D1	CLKOUT high to SDRAM address valid	t_{CHDAV}	—	9	ns
D2	CLKOUT high to SDRAM control valid	t_{CHDCV}	—	9	ns
D3	CLKOUT high to SDRAM address invalid	t_{CHDAI}	1.5	—	ns
D4	CLKOUT high to SDRAM control invalid	t_{CHDCI}	1.5	—	ns
D5	SDRAM data valid to CLKOUT high	t_{DDVCH}	4	—	ns
D6	CLKOUT high to SDRAM data invalid	t_{CHDDI}	1.5	—	ns
D7 ¹	CLKOUT high to SDRAM data valid	t_{CHDDVW}	—	9	ns
D8 ²	CLKOUT high to SDRAM data invalid	t_{CHDDIW}	1.5	—	ns

¹ D7 and D8 are for write cycles only.

General Purpose I/O Timing

Figure 15 shows an SDRAM write cycle.

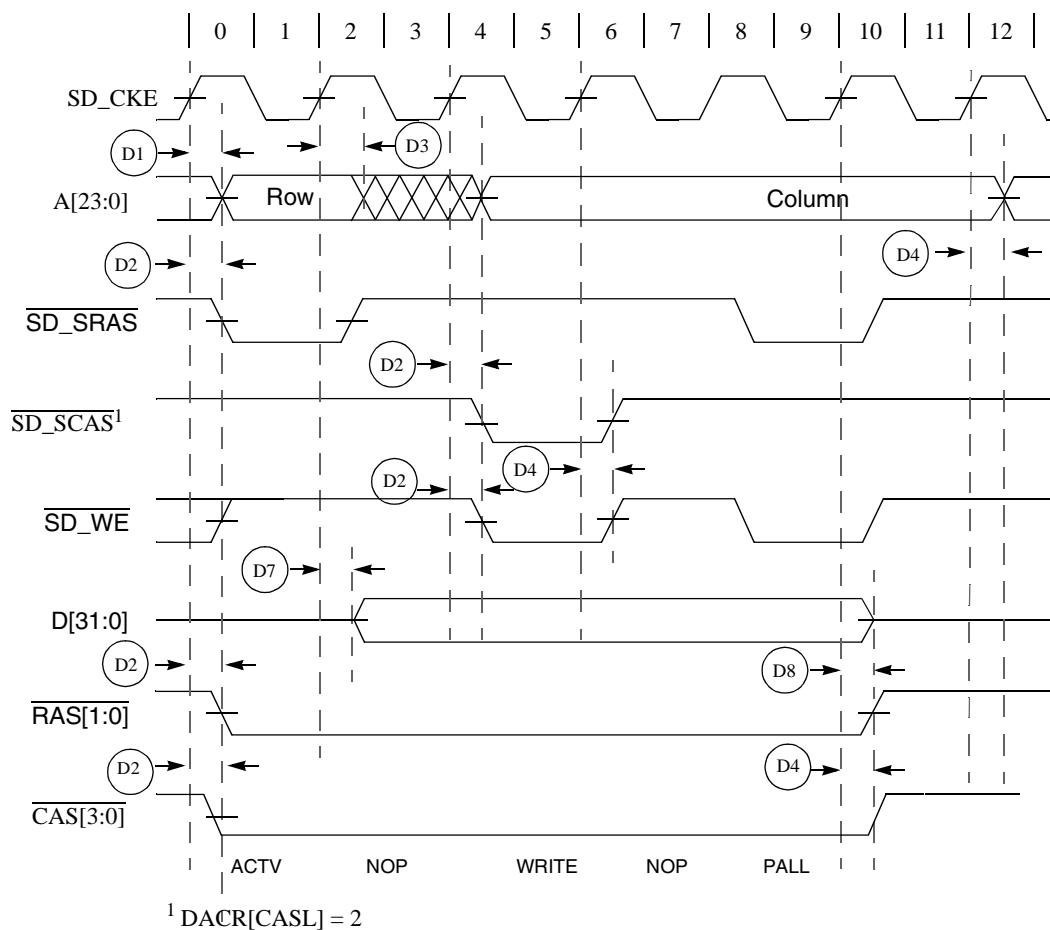


Figure 15. SDRAM Write Cycle

6.7 General Purpose I/O Timing

Table 49. GPIO Timing ¹

NUM	Characteristic	Symbol	Min	Max	Unit
G1 G2	CLKOUT High to GPIO Output Valid	t_{CHPOV}	—	10	ns
	CLKOUT High to GPIO Output Invalid	t_{CHPOI}	1.5	—	ns
G3 G4	GPIO Input Valid to CLKOUT High	t_{PVCH}	9	—	ns
	CLKOUT High to GPIO Input Invalid	t_{CHPI}	1.5	—	ns

¹ GPIO pins include: INT, ETPU, UART, FlexCAN and Timer pins.

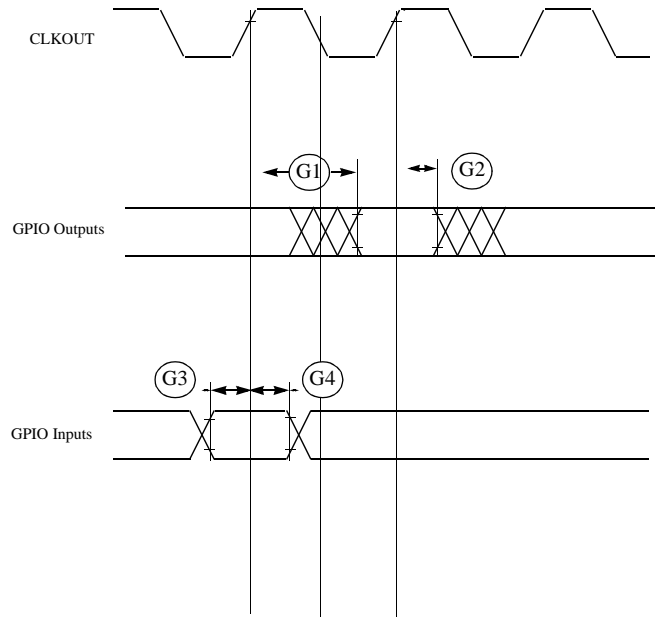


Figure 16. GPIO Timing

6.8 Reset and Configuration Override Timing

Table 50. Reset and Configuration Override Timing

($V_{DD} = 2.7$ to 3.6 V, $V_{SS} = 0$ V, $T_A = T_L$ to T_H)¹

NUM	Characteristic	Symbol	Min	Max	Unit
R1	\overline{RESET} Input valid to CLKOUT High	t_{RVCH}	9	—	ns
R2	CLKOUT High to \overline{RESET} Input invalid	t_{CHRI}	1.5	—	ns
R3	\overline{RESET} Input valid Time ²	t_{RIVT}	5	—	t_{CYC}
R4	CLKOUT High to \overline{RSTOUT} Valid	t_{CHROV}	—	10	ns
R5	\overline{RSTOUT} valid to Config. Overrides valid	t_{ROVCV}	0	—	ns
R6	Configuration Override Setup Time to \overline{RSTOUT} invalid	t_{COS}	20	—	t_{CYC}
R7	Configuration Override Hold Time after \overline{RSTOUT} invalid	t_{COH}	0	—	ns
R8	\overline{RSTOUT} invalid to Configuration Override High Impedance	t_{ROICZ}	—	1	t_{CYC}

¹ All AC timing is shown with respect to 50% V_{DD} levels unless otherwise noted.

² During low power STOP, the synchronizers for the \overline{RESET} input are bypassed and \overline{RESET} is asserted asynchronously to the system. Thus, \overline{RESET} must be held a minimum of 100 ns.

I²C Input/Output Timing Specifications

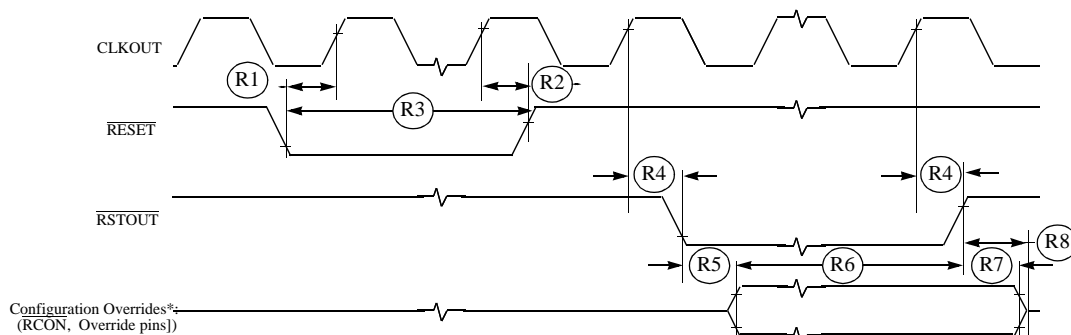


Figure 17. RESET and Configuration Override Timing

* Refer to the Coldfire Integration Module (CIM) section for more information.

6.9 I²C Input/Output Timing Specifications

Table 51 lists specifications for the I²C input timing parameters shown in Figure 18.

Table 51. I²C Input Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1	Start condition hold time	2	—	t_{cyc}
I2	Clock low period	8	—	t_{cyc}
I3	I2C_SCL/I2C_SDA rise time ($V_{IL} = 0.5$ V to $V_{IH} = 2.4$ V)	—	1	ms
I4	Data hold time	0	—	ns
I5	I2C_SCL/I2C_SDA fall time ($V_{IH} = 2.4$ V to $V_{IL} = 0.5$ V)	—	1	ms
I6	Clock high time	4	—	t_{cyc}
I7	Data setup time	0	—	ns
I8	Start condition setup time (for repeated start condition only)	2	—	t_{cyc}
I9	Stop condition setup time	2	—	t_{cyc}

Table 52 lists specifications for the I²C output timing parameters shown in Figure 18.

Table 52. I²C Output Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1 ¹	Start condition hold time	6	—	t_{cyc}
I2 ¹	Clock low period	10	—	t_{cyc}
I3 ²	I2C_SCL/I2C_SDA rise time ($V_{IL} = 0.5$ V to $V_{IH} = 2.4$ V)	—	—	μ s
I4 ¹	Data hold time	7	—	t_{cyc}
I5 ³	I2C_SCL/I2C_SDA fall time ($V_{IH} = 2.4$ V to $V_{IL} = 0.5$ V)	—	3	ns
I6 ¹	Clock high time	10	—	t_{cyc}

Table 52. I²C Output Timing Specifications between I2C_SCL and I2C_SDA

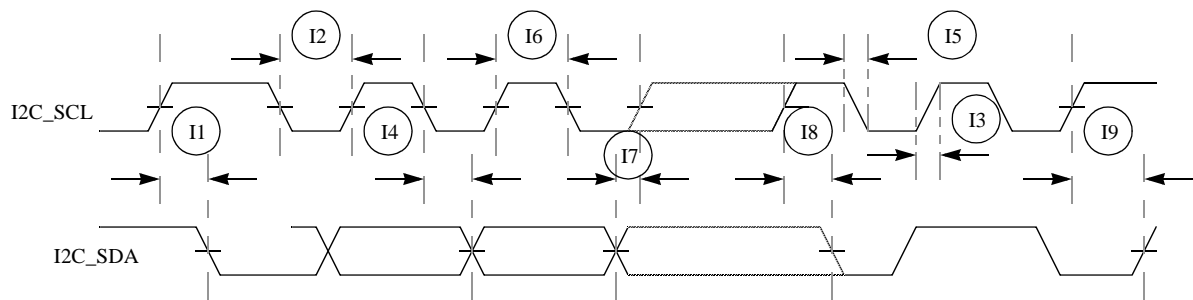
Num	Characteristic	Min	Max	Units
I7 ¹	Data setup time	2	—	t _{cyc}
I8 ¹	Start condition setup time (for repeated start condition only)	20	—	t _{cyc}
I9 ¹	Stop condition setup time	10	—	t _{cyc}

¹ Note: Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 52. The I²C interface is designed to scale the actual data transition time to move it to the middle of the I2C_SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 52 are minimum values.

² Because I2C_SCL and I2C_SDA are open-collector-type outputs, which the processor can only actively drive low, the time I2C_SCL or I2C_SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

³ Specified at a nominal 50-pF load.

Figure 18 shows timing for the values in Table 51 and Table 52.

**Figure 18. I²C Input/Output Timings**

6.10 Fast Ethernet AC Timing Specifications

MII signals use TTL signal levels compatible with devices operating at either 5.0 V or 3.3 V.

6.10.1 MII Receive Signal Timing (ERXD[3:0], ERXDV, ERXER, and ERXCLK)

The receiver functions correctly up to a ERXCLK maximum frequency of 25 MHz +1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed twice the ERXCLK frequency.

Table 53 lists MII receive channel timings.

Table 53. MII Receive Signal Timing

Num	Characteristic	Min	Max	Unit
M1	ERXD[3:0], ERXDV, ERXER to ERXCLK setup	5	—	ns
M2	ERXCLK to ERXD[3:0], ERXDV, ERXER hold	5	—	ns
M3	ERXCLK pulse width high	35%	65%	ERXCLK period
M4	ERXCLK pulse width low	35%	65%	ERXCLK period

Figure 19 shows MII receive signal timings listed in Table 53.

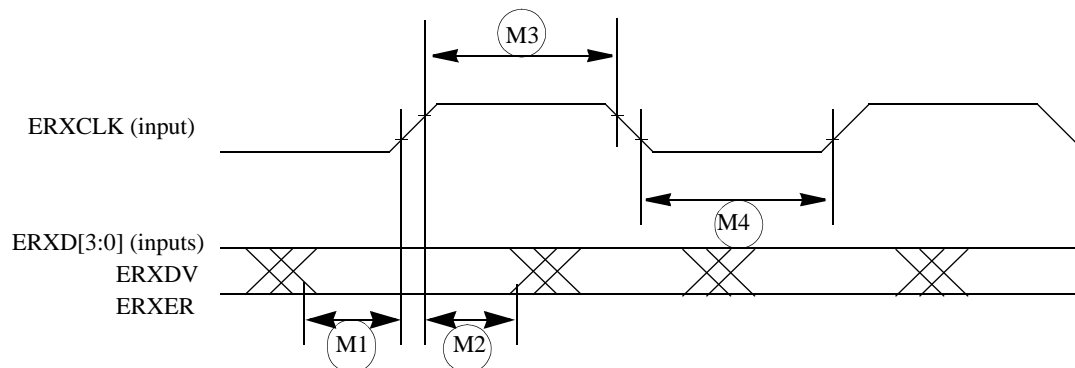


Figure 19. MII Receive Signal Timing Diagram

6.10.2 MII Transmit Signal Timing (ETXD[3:0], ETXEN, ETXER, ETXCLK)

Table 54 lists MII transmit channel timings.

The transmitter functions correctly up to a ETXCLK maximum frequency of 25 MHz +1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed twice the ETXCLK frequency.

The transmit outputs (ETXD[3:0], ETXEN, ETXER) can be programmed to transition from either the rising or falling edge of ETXCLK, and the timing is the same in either case. This options allows the use of non-compliant MII PHYs.

Refer to the Ethernet chapter for details of this option and how to enable it.

Table 54. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
M5	ETXCLK to ETXD[3:0], ETXEN, ETXER invalid	5	—	ns
M6	ETXCLK to ETXD[3:0], ETXEN, ETXER valid	—	25	ns
M7	ETXCLK pulse width high	35%	65%	ETXCLK period
M8	ETXCLK pulse width low	35%	65%	ETXCLK period

Figure 20 shows MII transmit signal timings listed in Table 54.

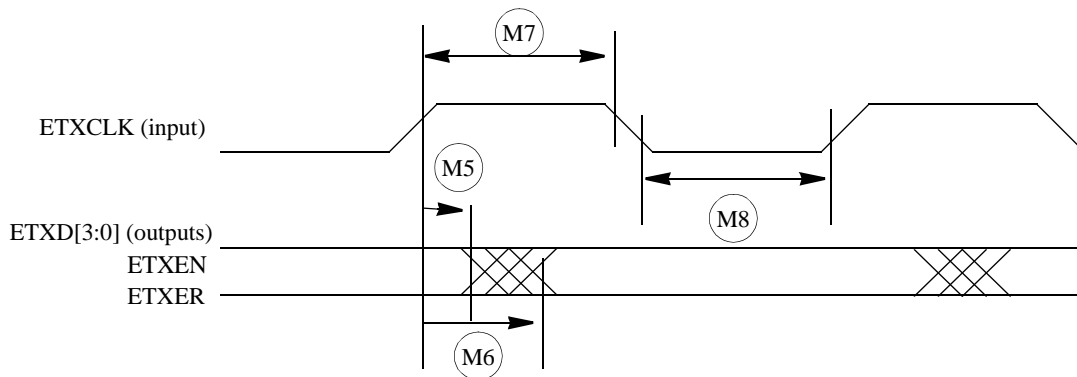


Figure 20. MII Transmit Signal Timing Diagram

6.10.3 MII Async Inputs Signal Timing (ECRS and ECOL)

Table 55 lists MII asynchronous inputs signal timing.

Table 55. MII Async Inputs Signal Timing

Num	Characteristic	Min	Max	Unit
M9	ECRS, ECOL minimum pulse width	1.5	—	ETXCLK period

Figure 21 shows MII asynchronous input timings listed in Table 55.

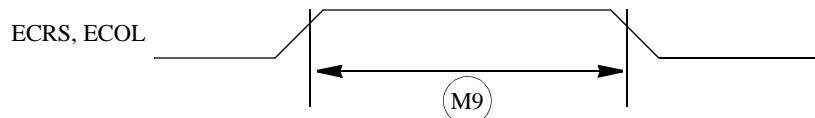


Figure 21. MII Async Inputs Timing Diagram

6.10.4 MII Serial Management Channel Timing (EMDIO and EMDC)

Table 56 lists MII serial management channel timings. The FEC functions correctly with a maximum MDC frequency of 2.5 MHz.

Table 56. MII Serial Management Channel Timing

Num	Characteristic	Min	Max	Unit
M10	EMDC falling edge to EMDIO output invalid (minimum propagation delay)	0	—	ns
M11	EMDC falling edge to EMDIO output valid (max prop delay)	—	25	ns
M12	EMDIO (input) to EMDC rising edge setup	10	—	ns
M13	EMDIO (input) to EMDC rising edge hold	0	—	ns
M14	EMDC pulse width high	40%	60%	MDC period
M15	EMDC pulse width low	40%	60%	MDC period

32-Bit Timer Module AC Timing Specifications

Figure 22 shows MII serial management channel timings listed in Table 56.

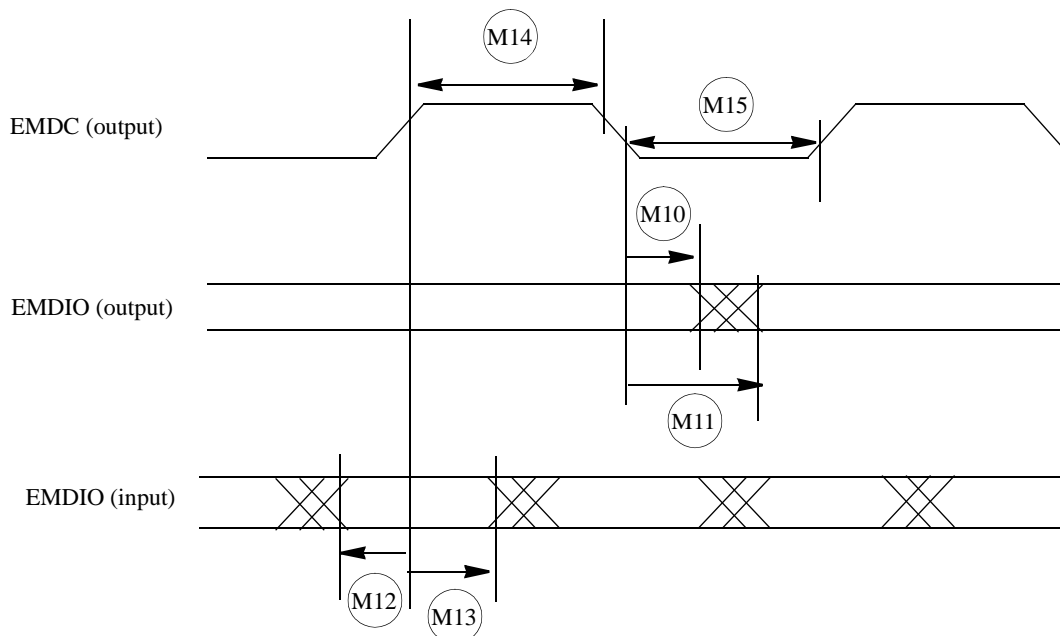


Figure 22. MII Serial Management Channel Timing Diagram

6.11 32-Bit Timer Module AC Timing Specifications

Table 57 lists timer module AC timings.

Table 57. Timer Module AC Timing Specifications

Name	Characteristic	0–66 MHz		Unit
		Min	Max	
T1	DTIN0 / DTIN1 / DTIN2 / DTIN3 cycle time	3	—	t_{CYC}
T2	DTIN0 / DTIN1 / DTIN2 / DTIN3 pulse width	1	—	t_{CYC}

6.12 QSPI Electrical Specifications

Table 58 lists QSPI timings.

Table 58. QSPI Modules AC Timing Specifications

Name	Characteristic	Min	Max	Unit
QS1	QSPI_CS[1:0] to QSPI_CLK	1	510	t_{cyc}
QS2	QSPI_CLK high to QSPI_DOUT valid.	—	10	ns
QS3	QSPI_CLK high to QSPI_DOUT invalid. (Output hold)	2	—	ns
QS4	QSPI_DIN to QSPI_CLK (Input setup)	9	—	ns
QS5	QSPI_DIN to QSPI_CLK (Input hold)	9	—	ns

The values in Table 58 correspond to Figure 23.

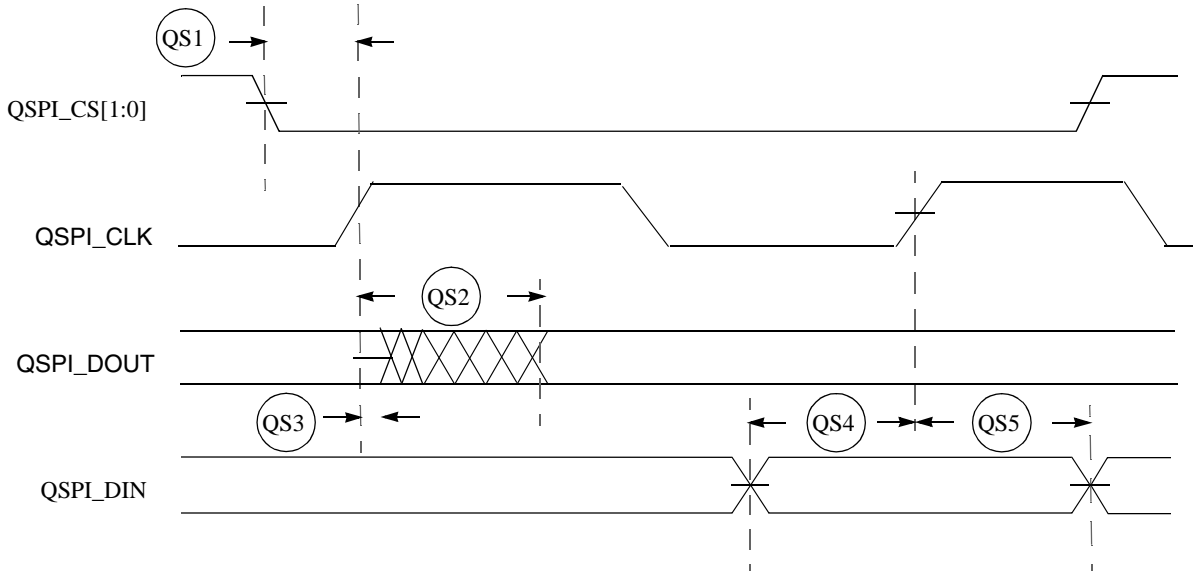


Figure 23. QSPI Timing

6.13 JTAG and Boundary Scan Timing

Table 59. JTAG and Boundary Scan Timing

Num	Characteristics ¹	Symbol	Min	Max	Unit
J1	TCLK Frequency of Operation	f_{JCYC}	DC	1/4	$f_{sys/2}$
J2	TCLK Cycle Period	t_{JCYC}	4	-	t_{CYC}
J3	TCLK Clock Pulse Width	t_{JCW}	26	-	ns
J4	TCLK Rise and Fall Times	t_{JCRF}	0	3	ns
J5	Boundary Scan Input Data Setup Time to TCLK Rise	t_{BSDST}	4	-	ns
J6	Boundary Scan Input Data Hold Time after TCLK Rise	t_{BSDHT}	26	-	ns
J7	TCLK Low to Boundary Scan Output Data Valid	t_{BSDV}	0	33	ns
J8	TCLK Low to Boundary Scan Output High Z	t_{BSDZ}	0	33	ns
J9	TMS, TDI Input Data Setup Time to TCLK Rise	t_{TAPBST}	4	-	ns
J10	TMS, TDI Input Data Hold Time after TCLK Rise	t_{TAPBHT}	10	-	ns
J11	TCLK Low to TDO Data Valid	t_{TDODV}	0	26	ns
J12	TCLK Low to TDO High Z	t_{TDODZ}	0	8	ns
J13	\overline{TRST} Assert Time	t_{TRSTAT}	100	-	ns
J14	\overline{TRST} Setup Time (Negation) to TCLK High	t_{TRSTST}	10	-	ns

¹ JTAG_EN is expected to be a static signal. Hence, specific timing is not associated with it.

JTAG and Boundary Scan Timing

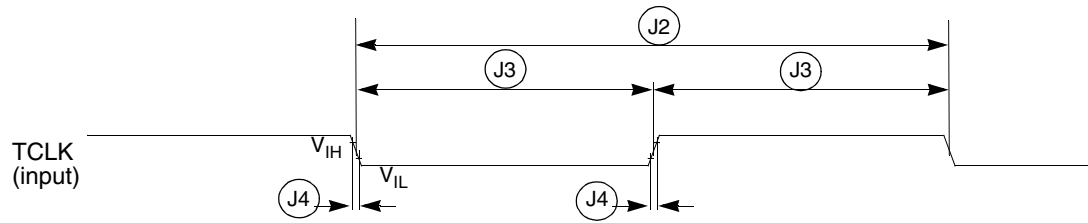


Figure 24. Test Clock Input Timing

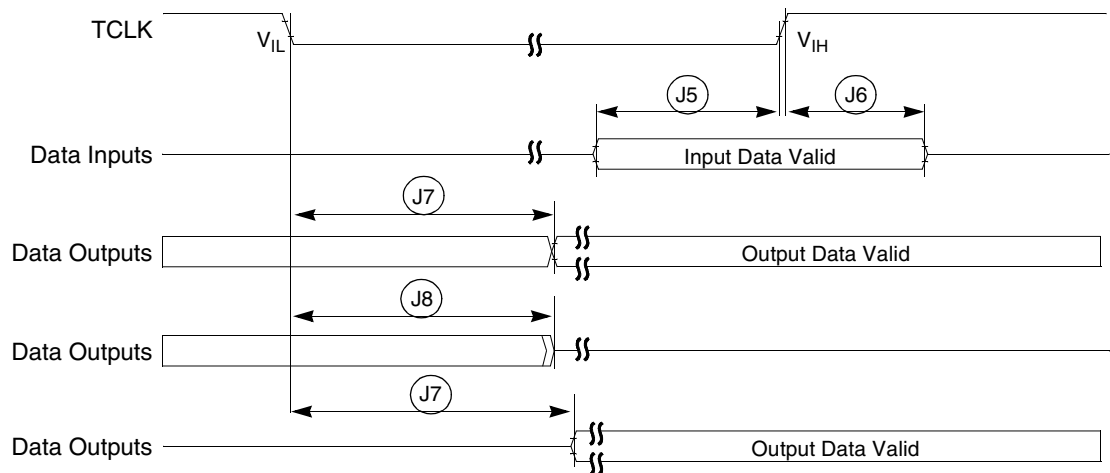


Figure 25. Boundary Scan (JTAG) Timing

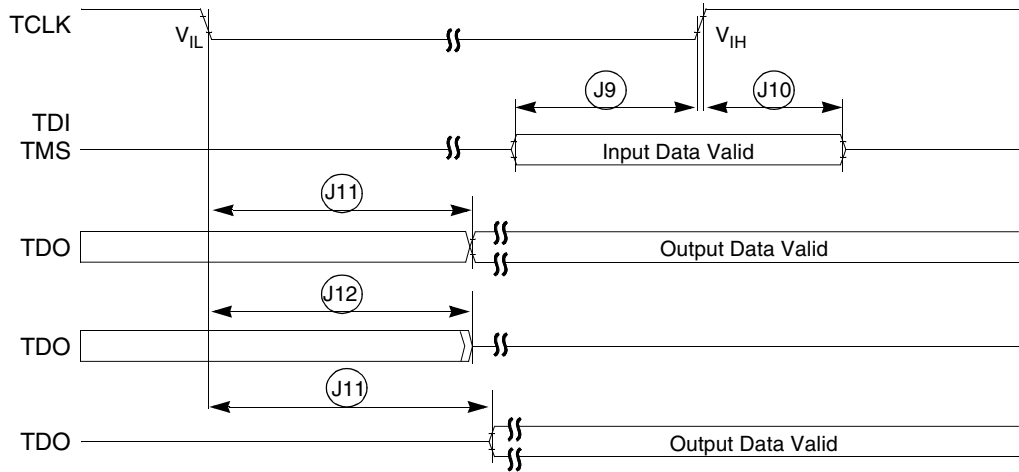


Figure 26. Test Access Port Timing

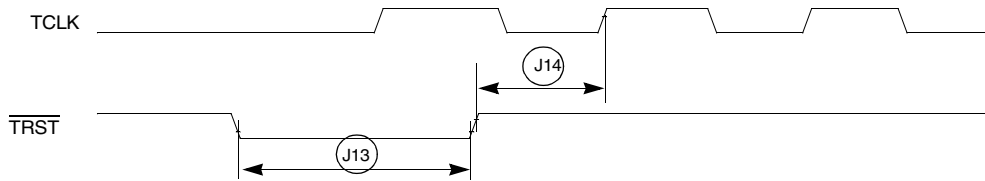


Figure 27. TRST Timing

6.14 Debug AC Timing Specifications

Table 60 lists specifications for the debug AC timing parameters shown in Figure 29.

Table 60. Debug AC Timing Specification

Num	Characteristic	150 MHz		Units
		Min	Max	
DE0	PSTCLK cycle time		0.5	t_{cyc}
DE1	PST valid to PSTCLK high	4		ns
DE2	PSTCLK high to PST invalid	1.5		ns
DE3	DSCLK cycle time	5		t_{cyc}
DE4	DSI valid to DSCLK high	1		t_{cyc}

Debug AC Timing Specifications

Table 60. Debug AC Timing Specification

Num	Characteristic	150 MHz		Units
		Min	Max	
DE5 ¹	DSCLK high to DSO invalid	4		t_{cyc}
DE6	\overline{BKPT} input data setup time to CLKOUT Rise	4		ns
DE7	CLKOUT high to \overline{BKPT} high Z	0	10	ns

¹ DSCLK and DSI are synchronized internally. D4 is measured from the synchronized DSCLK input relative to the rising edge of CLKOUT.

Figure 28 shows real-time trace timing for the values in Table 60.

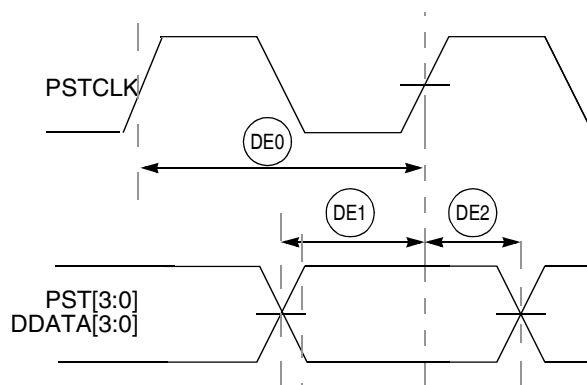


Figure 28. Real-Time Trace AC Timing

Figure 29 shows BDM serial port AC timing for the values in Table 60.

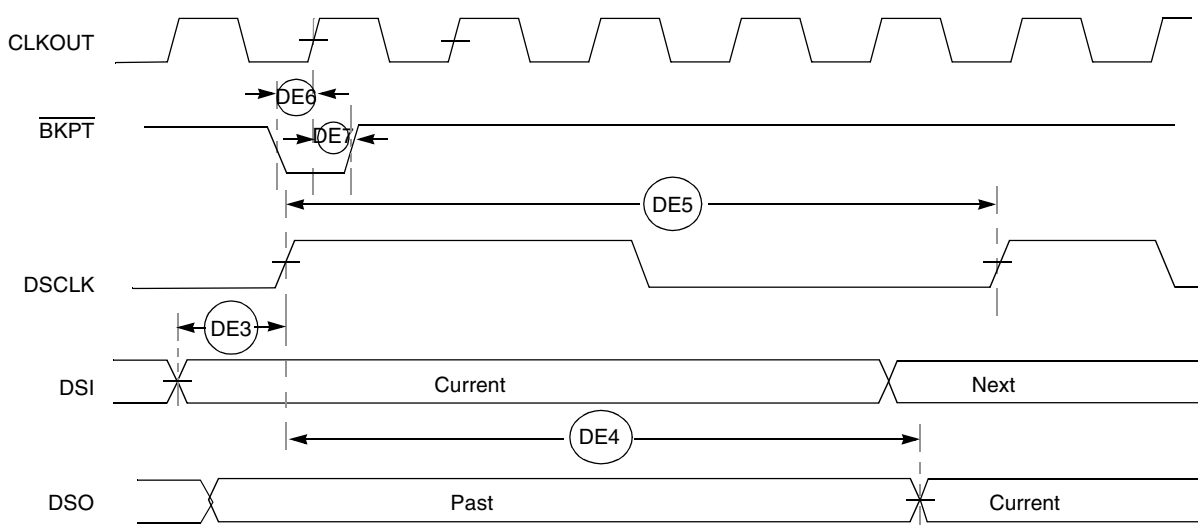


Figure 29. BDM Serial Port AC Timing

7 Documentation

Table 61 lists the documents that provide a complete description of the MCF523x and their development support tools. Documentation is available from a local Motorola distributor, a Motorola semiconductor sales office, the Motorola Literature Distribution Center, or through the Motorola world-wide web address at <http://www.motorola.com/semiconductors>.

Table 61. MCF523x Documentation

Motorola Document Number	Title	Revision	Status
MCF5232EC/D	MCF5232 RISC Microprocessor Hardware Specifications	0	This document
MCF5235RM/D	MCF523x Reference Manual	0	Available
MCF5235PB/D	MCF523x Product Brief	0	Available
MCF523xFS	MCF523x Fact Sheet	—	In Process
eTPURM/D	eTPU User Manual	—	In Process
CFPRODFACT/D	The ColdFire Family of 32-Bit Microprocessors Family Overview and Technology Roadmap	0	Available under NDA
MCF5xxxWP	MCF5xxxWP WHITE PAPER: Motorola ColdFire VL RISC Processors	0	Available under NDA
MAPBGAPP	MAPBGA 4-Layer Example	0	Available
CFPRM/D	ColdFire Family Programmer's Reference Manual	2	Available

7.1 Document Revision History

Table 62 provides a revision history for this document.

Table 62. Document Revision History

Rev. No.	Substantive Change(s)
0	Preliminary release.

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